

M5M29KB/T641AVP

**67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

DESCRIPTION

The M5M29KB/T641AVP are 3.3V-only high speed 67,108,864-bit CMOS boot block FLASH Memories with alternating BGO(Back Ground Operation) feature. The BGO feature of the device allows Program or Erase operations to be performed in one bank while the device simultaneously allows Read operations to be performed on the other bank.

This BGO feature is suitable for mobile and personal computing, and communication products.

The M5M29KB/T641AVP are fabricated by CMOS technology for the peripheral circuit and DINOR IV(Divided bit-line NOR IV) architecture for the memory cell, and are available in 48pin TSOP(I) for lead free use.

M5M29KB/T641AVP provides for Software Lock Release function. Usually, all memory blocks are locked and can not be programmed or erased, when WP# is low. Using Software Lock Release function, program or erase operation can be executed.

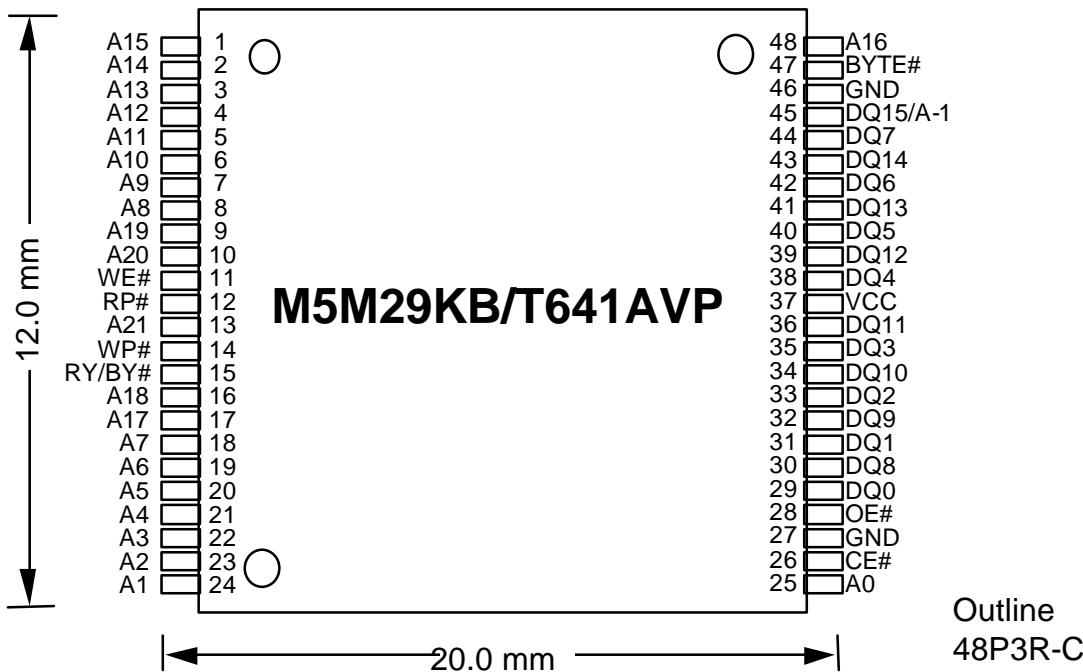
FEATURES

Access time	Flash	70ns (Max.)
Supply voltage	VCC= 3.0 ~ 3.6V	
Ambient temperature	Ta=-40 ~ 85 °C	
Package	48pin TSOP(Type-I), Lead pitch 0.5mm Outer-lead finishing : Sn-Cu	

APPLICATION

Digital Cellular Phone, Telecommunication,
PDA, Car Navigation System, Video Game Machine

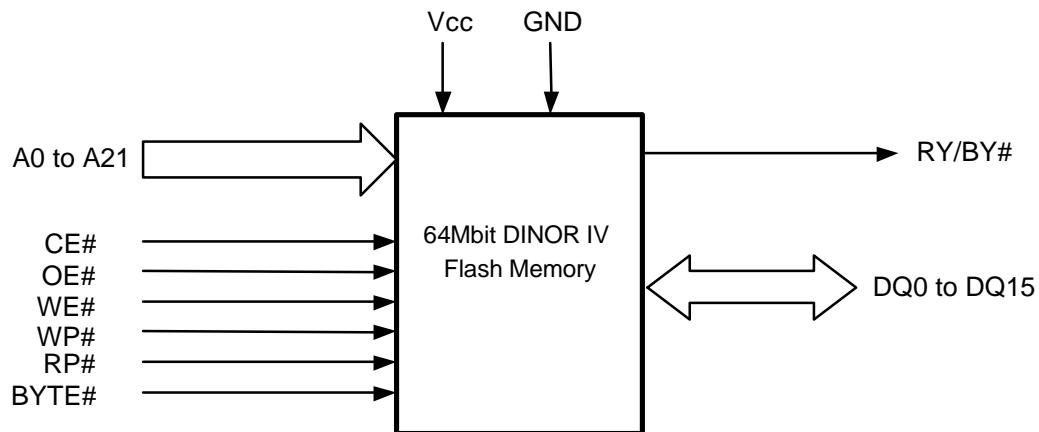
PIN CONFIGURATION (TOP VIEW)



VCC	: VCC	WE#	: Write enable
GND	: GND	WP#	: Write protect
A0-A21	: Address	RP#	: Reset power down
DQ0-DQ15	: Data I/O	BYTE#	: Byte enable
CE#	: Chip enable	RY/BY#	: Ready/Busy
OE#	: Output enable		

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64M Flash Memory Block Diagram**Capacitance**

Symbol	Parameter	Conditions	Limits			Unit
			Min.	Typ.	Max.	
CIN	Input capacitance A21-A0, OE#, WE#, CE#, WP#, RP#,BYTE#	Ta=25°C, f=1MHz, Vin=Vout=0V			12	pF
COUT	Output Capacitance DQ15-DQ0,RY/BY#				12	pF

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Flash Memory Part**Description**

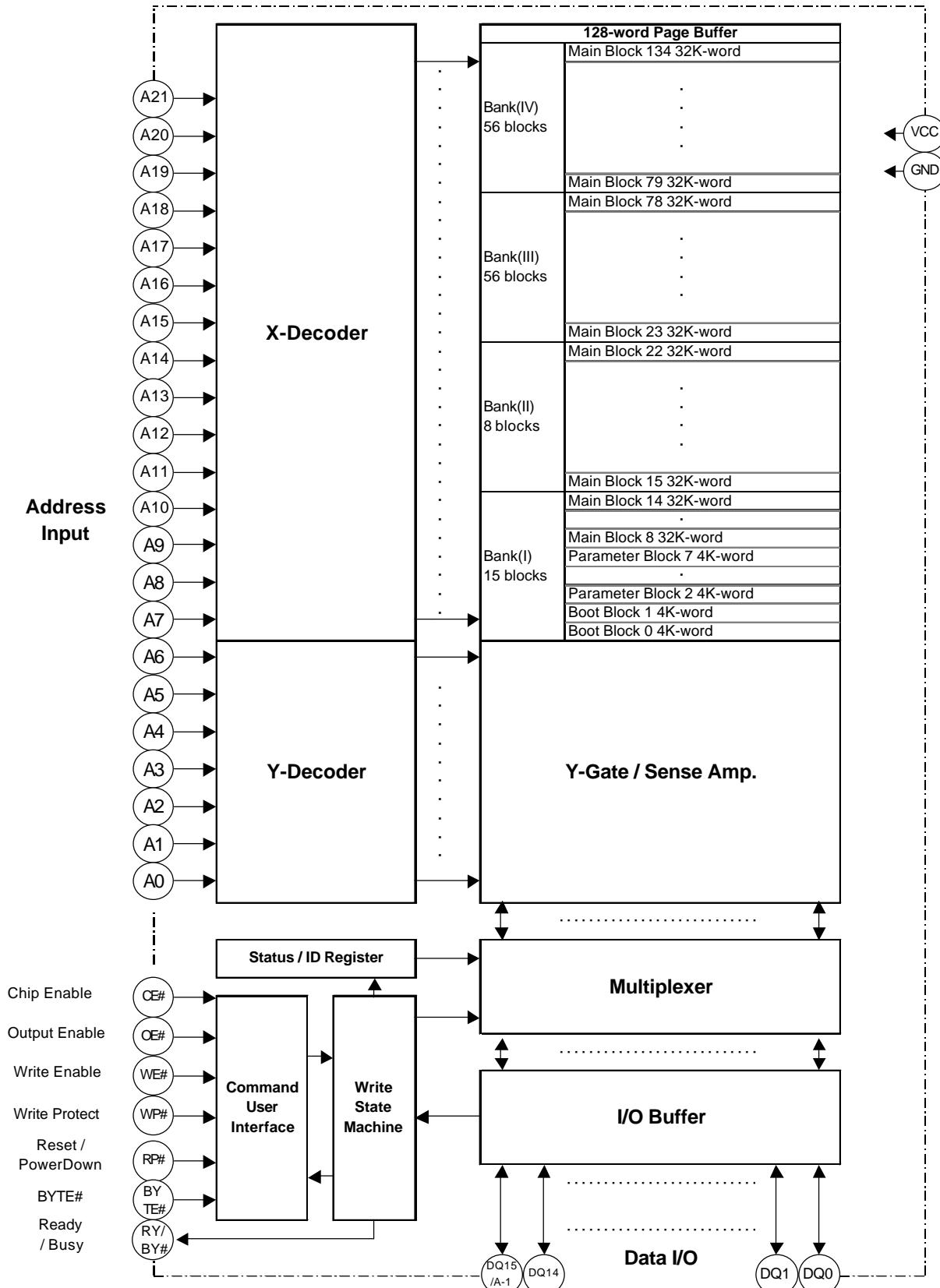
The 64M-bit DINOR IV(Divided bit line NOR IV) Flash Memory is 3.3V-only high speed 67,108,864-bit CMOS boot block Flash Memory. Alternating BGO(Back Ground Operation) feature of the device allows Program or Erase operations to be performed in one bank while the device simultaneously allows Read operations to be performed on the other bank. This BGO feature is suitable for communication products and cellular phone. The Flash Memory is fabricated by CMOS technology for the peripheral circuits and DINOR IV architecture for the memory cells.

Features

- Organization	4,194,304-word x 16-bit 8,388,608-word x 8-bit	- Auto Erase	Erase time	150ms(typ.)
- Supply Voltage	VCC = 3.0 ~ 3.6V	Erase unit	Bank(I)	Boot Block 4K-word /8K-byte x 2 Parameter Block 4K-word /8K-byte x 6 Main Block 32K-word /64K-byte x 7
- Access time		Bank(II)	Main Block	32K-word /64K-byte 8
Random Access	70ns(Max.)	Bank(III)	Main Block	32K-word /64K-byte x 56
Random Page Read	25ns(Max.)	Bank(IV)	Main Block	32K-word /64K-byte x 56
Read	108mW (Max. at 5MHz)	- Program/Erase cycles		100Kcycles
(After Automatic Power Down)	0.33μW(typ.)	- Boot Block	Bottom Boot	M***B6*****
- Program/Erase	126mW(Max.)		Top Boot	M***T6*****
Standby	0.33μW(typ.)	- The Other Functions		Software Command Control Quick Data Reclaim Software Lock Release(while WP# is low) Erase Suspend/Resume Program Suspend/Resume Status Register Read Alternating Back Ground Program/Erase Operation Between Bank(I), Bank(II), Bank(III) and Bank(IV) Random Page Read
Deep Power Down mode	0.33μW(typ.)			
- Auto Program for Bank(I) – Bank(IV)				
Program Time				
Word Program	30μs/1word(typ.)			
Byte Program	30μs/1byte(typ.)			
Page Program	4ms(typ.)			
Program Unit				
Word Program	1 word			
Byte Program	1 byte			
Page Program	128 words/256 bytes			

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Block Diagram (64Mbit Flash Memory)

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Function of Flash Memory

The 64M-bit DINOR IV Flash Memory includes on-chip program/erase control circuitry. The Write State Machine (WSM) controls block erase and word/page program operations. Operational modes are selected by the commands written to the Command User Interface (CUI). The Status Register indicates the status of the WSM and when the WSM successfully completes the desired program or block erase operation.

A Deep Power Down mode is enabled when the RP# pin is at GND, minimizing power consumption.

Read

The 64M-bit DINOR IV Flash Memory has four read modes, which accesses to the memory array ,the Page read, the Device Identifier and the Status Register. The appropriate read commands are required to be written to the CUI. Upon initial device power up or after exit from deep power down, the 64M-bit DINOR IV Flash Memory automatically resets to read array mode. In the read array mode and in the conditions are low level input to OE#, high level input to WE# and RP#, low level input to CE# and address signals to the address inputs (A21 - A0:Word Mode, A21-A-1:Byte Mode) the data of the addressed location to the data input/output (DQ15-DQ0:Word Mode, DQ7-DQ0:Byte Mode) is output.

Write

Writes to the CUI enables reading of memory array data, device identifiers and reading and clearing of the Status Register. They also enable block erase and program. The CUI is written by bringing WE# to low level and OE# is at high level, while CE# is at low level. Address and data are latched on the earlier rising edge of WE# and CE#. Standard micro processor write timings are used.

Alternating Background Operation (BGO)

The 64M-bit DINOR IV Flash Memory allows to read array from one bank while the other bank operates in software command write cycling or the erasing / programming operation in the background. Array Read operation with the other bank in BGO is performed by changing the bank address without any additional command. When the bank address points the bank in software command write cycling or the erasing / programming operation, the data is read out from the status register. The access time with BGO is the same as the normal read operation. BGO must be between Bank(I), Bank(II), Bank(III) and Bank(IV).

Output Disable

When OE# is at VIH, output from the devices is disabled. Data input/output are in a high-impedance (High-Z) state.

Standby

When CE# is at VIH, the device is in the standby mode and its power consumption is reduced. Data input/output are in a high-impedance (High-Z) state. If the memory is deselected during block erase or program, the internal control circuits remain active and the device consumes normal active power until the operation completes.

Deep Power Down

When RP# is at VIL, the device is in the deep power down mode and its power consumption is substantially low. During read modes, the memory is deselected and the data input/output are in a high-impedance (High-Z) state. After return from power down, the CUI is reset to Read Array, and the Status Register is cleared to value 80H.

During block erase or program modes, RP# low will abort either operation. Memory array data of the block being altered become invalid.

Automatic Power Down (Auto-PD)

The Automatic Power Down minimizes the power consumption during read mode. The device automatically turns to this mode when any addresses or CE# isn't changed more than 200ns after the last alternation. The power consumption becomes the same as the stand-by mode. During this mode, the output data is latched and can be read out. New data is read out correctly when addresses are changed.

BBR(Back Bank array Read)

In the 64M-bit DINOR IV Flash Memory , when one memory address is read according to a Read Mode in the case of the same as an access when a Read Mode command is input, an another Bank memory data can be read out (Read Array or Page Read) by changing an another Bank address.

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Software Command Definitions

The device operations are selected by writing specific software command into the Command User Interface.

Read Array Command (FFH)

The device is in Read Array mode on initial device power up and after exit from deep power down, or by writing FFH to the Command User Interface. After starting the internal operation the device is set to the read status register mode automatically.

Read Device Identifier Command (90H)

We can normally read device identifier codes when Read Device Identifier Code Command (90H) is written to the command latch. Following the command write, the manufacturer code and the device code can be read from A0 address 0H and 1H in a bank address, respectively.

Read Status Register Command (70H)

The Status Register is read after writing the Read Status Register command of 70H to the Command User Interface. Also, after starting the internal operation the device is set to the Read Status Register mode automatically.

The contents of Status Register are latched on the later falling edge of OE# must be toggled every status read.

Page Read Command (F3H)

The Page Read command (F3H) timing can be used by writing the first command to CUI and F-CE# falls VIL or changing the address(A21-A2) is necessary to start activating page read mode. This command is fast random 4 words read. During the read it is necessary to fix F-CE# low and change addresses that are defined by A0 and A1(0h - 3h) at random continuously. The mode is kept until F-RP# is set to L or this chip is powered down.

The first read of Page Read timing is the same as normal read (ta(CE)). F-CE# should be fallen "L". The read timing after the first is the same as ta(PAD).

In the page read mode the upper address(A21-A2) or F-CE# are supposed not to be clocked during read operation. Otherwise the access time is as same as normal read.

Clear Status Register Command (50H)

The Erase Status, Program Status and Block Status bits are set to "1"s by the Write State Machine and can only be reset by the Clear Status Register command of 50H. These bits indicate various failure conditions.

Block Erase / Confirm Command (20H/D0H)

Automated block erase is initiated by writing the Block Erase command of 20H followed by the Confirm command of D0H. An address within the block to be erased is required. The WSM executes iterative erase pulse application and erase verify operation.

Program Commands

A) Word / Byte Program (40H)

Word/Byte program is executed by a two-command sequence. The Word/Byte program Setup command of 40H is written to the Command Interface, followed by a second write specifying the address and data to be written. The WSM controls the program pulse application and verify operation.

B) Page Program for Data Blocks (41H)

Page Program allows fast programming of 128words of data. Writing of 41H initiates the page program operation for the Data area. From 2nd cycle to 129th cycle, write data must be serially inputted. Address A6-A0 have to be incremented from 00H to 7FH. After completion of data loading, the WSM controls the program pulse application and verify operation.

C) Single Data Load to Page Buffer (74H)

/ Page Buffer to Flash (0EH/D0H)

Single data load to the page buffer is performed by writing 74H followed by a second write specifying the column address and data. Distinct data up to 128word can be loaded to the page buffer by this two-command sequence. On the other hand, all of the loaded data to the page buffer is programmed simultaneously by writing Page Buffer to Flash command of 0EH followed by the confirm command of D0H. After completion of programming the data on the page buffer is cleared automatically.

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Flash to Page Buffer Command (F1H/D0H)

Array data load to the page buffer is performed by writing the Flash to Page Buffer command of F1H followed by the Confirm command of D0H. An address within the page to be loaded is required. Then the array data can be copied into the other pages within the same bank by using the Page Buffer to Flash command.

Clear Page Buffer Command (55H/D0H)

Loaded data to the page buffer is cleared by writing the Clear Page Buffer command of 55H followed by the Confirm command of D0H. This command is valid for clearing data loaded by Single Data Load to Page Buffer command.

Data Protection

The 64M-bit DINOR IV Flash Memory has a master Write Protect pin (WP#). When WP# is at VIH, all blocks can be programmed or erased. When WP# is low, all blocks are in locked mode which prevents any modifications to memory blocks. Software Lock Release function is only command which allows to program or erase.

Suspend/Resume Command (B0H/D0H)

Writing the Suspend command of B0H during block erase operation interrupts the block erase operation and allows read out from another block of memory. Writing the Suspend command of B0H during program operation interrupts the program operation and allows read out from another block of memory. The Bank address is required when writing the Suspend/Resume Command. The device continues to output Status Register data when read, after the Suspend command is written to it. Polling the WSM Status and Suspend Status bits will determine when the erase operation or program operation has been suspended. At this point, writing of the Read Array command to the CUI enables reading data from blocks other than that which is suspended. When the Resume command of D0H is written to the CUI, the WSM will continue with the erase or program processes.

Erase All Unlocked Blocks Command (A7H/D0H)

The command sequence enable us to erase all blocks. The command can be used by writing Setup command A7H(1st cycle) and confirm command D0H(2nd cycle). The sequence is not valid in case of WP#=VIL.

Power Supply Voltage

When the power supply voltage is less than VLKO, Low VCC Lock-Out voltage, the device is set to the Read-only mode.

A delay time of 60μs is required before any device operation is initiated. The delay time is measured from the time Flash VCC reaches Flash VCCmin (3.0V).

During power up, RP# = GND is recommended. Falling in Busy status is not recommended for possibility of damaging the device.

Memory Organization

The 64M-bit DINOR IV Flash Memory is constructed by 2 boot blocks of 4K words, 6 parameter blocks of 4K words and 7 main blocks of 32K words in Bank(I), by 8 main blocks of 32K words in Bank(II) and by 56 main blocks of 32K words in Bank(III) and Bank(IV).

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Block Organization

x8 (Byte Mode)	x16 (Word Mode)
1A0000H- D0000H-	32Kword 33
1AFFFFH D7FFFH	32Kword 32
190000H- C8000H-	32Kword 31
19FFFFH CFFFFH	32Kword 30
180000H- C0000H-	32Kword 29
18FFFH C7FFFH	32Kword 28
170000H- B8000H-	32Kword 27
17FFFFH BFFFFH	32Kword 26
160000H- B0000H-	32Kword 25
16FFFH B7FFFH	32Kword 24
150000H- A8000H-	32Kword 23
15FFFH AFFFFF	32Kword 22
140000H- A0000H-	32Kword 21
14FFFH A7FFFH	32Kword 20
130000H- 98000H-	32Kword 19
13FFFH 9FFFH	32Kword 18
120000H- 90000H-	32Kword 17
12FFFH 97FFFH	32Kword 16
110000H- 88000H-	32Kword 15
11FFFH 8FFFH	32Kword 14
100000H- 80000H-	32Kword 13
10FFFH 87FFFH	32Kword 12
F0000H- 78000H-	32Kword 11
FFF00H- 7FFFH	32Kword 10
E0000H- 70000H-	32Kword 9
EFFFFFH 77FFFH	32Kword 8
D0000H- 68000H-	32Kword 7
DFFFH 6FFFH	32Kword 6
C0000H- 60000H-	32Kword 5
CFFFH 67FFFH	32Kword 4
B0000H- 58000H-	32Kword 3
BFFFH 5FFFH	32Kword 2
A0000H- 50000H-	32Kword 1
AFFFH 57FFFH	32Kword 0
90000H- 48000H-	
9FFFH 4FFFH	
80000H- 40000H-	
8FFFH 47FFFH	
70000H- 38000H-	
7FFFH 3FFFH	
60000H- 30000H-	
6FFFH 37FFFH	
50000H- 28000H-	
5FFFH 2FFFH	
40000H- 20000H-	
4FFFH 27FFFH	
30000H- 18000H-	
3FFFH 1FFFH	
20000H- 10000H-	
2FFFH 17FFFH	
10000H- 08000H-	
1FFFH 0FFFH	
0E000H- 07000H-	
0FFFH 07FFFH	
0C000H- 06000H-	
0DFFH 06FFFH	
0A000H- 05000H-	
0BFFFH 05FFFH	
08000H- 04000H-	
09FFFH 04FFFH	
06000H- 03000H-	
07FFFH 03FFFH	
04000H- 02000H-	
05FFFH 02FFFH	
02000H- 01000H-	
03FFFH 01FFFH	
00000H- 00000H-	
01FFFH 00FFFH	

64M-bit DINOR(IV) Flash Memory Map (Bottom Boot)

x8 (Byte Mode)	x16 (Word Mode)	x8 (Byte Mode)	x16 (Word Mode)	x8 (Byte Mode)	x16 (Word Mode)
3C0000H- 1E0000H-	32Kword 67	5E0000H- 2F0000H-	32Kword 101	7F0000H- 3F8000H-	32Kword 134
3CFFFFH 1E7FFFH	32Kword 66	5EFFFH 2F7FFFH	32Kword 100	7FFFFFFH 3FFFFFFH	32Kword 133
3B0000H- 1D8000H-	32Kword 65	5D0000H- 2E8000H-	32Kword 99	7E0000H- 3F0000H-	32Kword 132
3BFFFH 1DFFFH	32Kword 64	5DFFFH 2EFFFH	32Kword 98	7EFFFH 3F7FFFH	32Kword 131
3A0000H- 1D0000H-	32Kword 63	5C0000H- 2E0000H-	32Kword 97	7D0000H- 3E8000H-	32Kword 130
3AFFFH 1D7FFFH	32Kword 62	5CFFFFH 2E7FFFH	32Kword 96	7DFFFH 3EFFFFH	32Kword 129
390000H- 1C8000H-	32Kword 61	5B0000H- 2D8000H-	32Kword 95	7C0000H- 3E0000H-	32Kword 128
39FFFH 1CFFFFH	32Kword 60	5A0000H- 2D0000H-	32Kword 94	790000H- 3C8000H-	32Kword 127
380000H- 1C0000H-	32Kword 59	5AFFFH 2D7FFFH	32Kword 93	780000H- 3C0000H-	32Kword 126
38FFFH 1C7FFFH	32Kword 58	590000H- 2C8000H-	32Kword 92	78FFFH 3C7FFFH	32Kword 125
350000H- 1A8000H-	32Kword 57	59FFFH 2CFFFFH	32Kword 91	750000H- 3A8000H-	32Kword 124
35FFFH 1AFFFFH	32Kword 56	5A0000H- 2B8000H-	32Kword 90	75FFFH 3AFFFFH	32Kword 123
340000H- 1A0000H-	32Kword 55	5B0000H- 2B7FFFH	32Kword 89	740000H- 3A0000H-	32Kword 122
34FFFH 1A7FFFH	32Kword 54	5C0000H- 298000H-	32Kword 88	730000H- 3A7FFFH	32Kword 121
300000H- 1B8000H-	32Kword 53	5D0000H- 299000H-	32Kword 87	720000H- 390000H-	32Kword 120
30FFFH 1B7FFFH	32Kword 52	5E0000H- 290000H-	32Kword 86	72FFFH 397FFFH	32Kword 119
2F0000H- 178000H-	32Kword 51	5F0000H- 280000H-	32Kword 85	710000H- 388000H-	32Kword 118
2FFFH 177FFFH	32Kword 50	60000H- 287FFFH	32Kword 84	71FFFH 38FFFFH	32Kword 117
2E0000H- 170000H-	32Kword 49	64000H- 278000H-	32Kword 83	70000H- 380000H-	32Kword 116
2EFFFH 177FFFH	32Kword 48	6C0000H- 268000H-	32Kword 82	70FFFH 387000H-	32Kword 115
2D0000H- 168000H-	32Kword 47	6D0000H- 260000H-	32Kword 81	6F0000H- 378000H-	32Kword 114
2DFFFH 167FFFH	32Kword 46	6E0000H- 250000H-	32Kword 80	6FFFH 37FFFH	32Kword 113
2C0000H- 160000H-	32Kword 45	6F0000H- 255FFFH	32Kword 79	6E0000H- 370000H-	32Kword 112
2CFFFH 167FFFH	32Kword 44	70000H- 257FFFH	32Kword 78	6EFFFH 377FFFH	32Kword 111
260000H- 130000H-	32Kword 43	710000H- 259FFFH	32Kword 77	6D0000H- 368000H-	32Kword 110
26FFFH 137FFFH	32Kword 42	720000H- 260000H-	32Kword 76	6DFFFH 36FFFH	32Kword 109
250000H- 128000H-	32Kword 41	730000H- 267FFFH	32Kword 75	6C0000H- 360000H-	32Kword 108
25FFFH 12FFFH	32Kword 40	740000H- 276FFFH	32Kword 74	6CFFFH 367FFFH	32Kword 107
240000H- 120000H-	32Kword 39	750000H- 277FFFH	32Kword 73	6B0000H- 358000H-	32Kword 106
24FFFH 127FFFH	32Kword 38	760000H- 278FFFH	32Kword 72	6BFFFH 35FFFH	32Kword 105
230000H- 118000H-	32Kword 37	770000H- 279FFFH	32Kword 71	6A0000H- 350000H-	32Kword 104
23FFFH 11FFFH	32Kword 36	780000H- 280FFFH	32Kword 70	6AFFFH 357FFFH	32Kword 103
220000H- 110000H-	32Kword 35	790000H- 281FFFH	32Kword 69	690000H- 348000H-	32Kword 102
22FFFH 117FFFH	32Kword 34	7A0000H- 282FFFH	32Kword 68	69FFFH 34FFFH	
1F0000H- F8000H-	A21-A1	A21-A0	A21-A1	A21-A0	
1FFFH FFFFFH	(Byte Mode)	(Word Mode)	(Byte Mode)	(Word Mode)	
1E0000H- F0000H-					
1EFFFH F7FFFH					
1D0000H- E8000H-					
1DFFFH EFFFFH					
1C0000H- E0000H-					
1CFFFH E7FFFH					
1B0000H- D8000H-					
1BFFFH DFFFFH					

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Block Organization

x8 (Byte Mode)	x16 (Word Mode)
210000H-21FFFFH	108000H-10FFFFH
200000H-20FFFFH	100000H-107FFFH
1F0000H-F8000H	FFFFFH
1FFFFFFH	F8000H
1E0000H-F0000H	F0000H
1EFFFFFH	F7FFFH
1D0000H-E8000H	E8000H
1DFFFFFFH	EFFFFFH
1C0000H-E0000H	
1CFFFFH	E7FFFH
1B0000H-D8000H	D8000H
1BFFFFFFH	DFFFFH
1A0000H-D0000H	
1AFFFFFH	D7FFFH
190000H-C8000H	C8000H
19FFFFFFH	CFFFFH
180000H-C0000H	C0000H
18FFFFFFH	C7FFFH
170000H-B8000H	B8000H
17FFFFFFH	BFFFFH
160000H-B0000H	
16FFFFFFH	B7FFFH
150000H-A8000H	A8000H
15FFFFFFH	AFFFFH
140000H-A0000H	
14FFFFFFH	A7FFFH
130000H-98000H	98000H
13FFFFFFH	9FFFH
120000H-90000H	90000H
12FFFFFFH	97FFFH
110000H-88000H	88000H
11FFFFFFH	8FFFH
100000H-80000H	80000H
10FFFFFFH	87FFFH
F0000H-78000H	
FFFFFFFH	7FFFH
E0000H-70000H	70000H
EFFFFFH	77FFFH
D0000H-68000H	68000H
DFFFFFFH	6FFFH
C0000H-60000H	60000H
CFFFFFFH	67FFFH
B0000H-58000H	58000H
BFFFFFFH	5FFFH
A0000H-50000H	50000H
AFFFFFFH	57FFFH
90000H-48000H	48000H
9FFFFFFH	4FFFH
80000H-40000H	40000H
8FFFFFFH	47FFFH
70000H-38000H	38000H
7FFFFFFH	3FFFH
60000H-30000H	30000H
6FFFFFFH	37FFFH
50000H-28000H	28000H
5FFFFFFH	2FFFH
40000H-20000H	20000H
4FFFFFFH	17FFFH
2D0000H-168000H	168000H
2DFFFFFFH	16FFFH
2C0000H-160000H	160000H
2CFFFFFFH	167FFFH
2B0000H-158000H	158000H
2BFFFFFFH	15FFFH
2A0000H-150000H	150000H
2AFFFFFH	157FFFH
290000H-148000H	148000H
29FFFFFFH	14FFFH
280000H-140000H	140000H
28FFFFFFH	147FFFH
270000H-138000H	138000H
27FFFFFFH	13FFFH
260000H-130000H	130000H
26FFFFFFH	137FFFH
250000H-128000H	128000H
25FFFFFFH	12FFFH
240000H-120000H	120000H
24FFFFFFH	127FFFH
230000H-118000H	118000H
23FFFFFFH	11FFFH
220000H-110000H	110000H
22FFFFFFH	117FFFH
A21-A-1	A21-A0
(Byte Mode)	(Word Mode)
32Kword 34	

64M-bit DINOR(IV) Flash Memory Map (Top Boot)

x8 (Byte Mode)	x16 (Word Mode)	x8 (Byte Mode)	x16 (Word Mode)	x8 (Byte Mode)	x16 (Word Mode)	x8 (Byte Mode)	x16 (Word Mode)	BANK(I)
430000H-218000H	21FFFFFFH	32Kword 67		650000H-328000H	32Kword 101	7FE000H-4Kword 134		
43FFFFFFH	21FFFFFFH	32Kword 66		65FFFFFFH	32Kword 100	7FFFFFFH-4Kword 133		
420000H-210000H	217FFFH	32Kword 65		640000H-320000H	32Kword 99	7FC000H-4Kword 132		
410000H-208000H	20FFFH	32Kword 64		630000H-318000H	32Kword 98	7FDFFFH-4Kword 131		
41FFFFFFH	20FFFH	32Kword 63		620000H-310000H	32Kword 97	7FBFFFH-4Kword 130		
3F0000H-1F8000H	1F8000H	32Kword 62		610000H-308000H	32Kword 96	7F8000H-4Kword 129		
3FFFFFFFH	1F8000H	32Kword 61		5F0000H-2F8000H	32Kword 95	7F2000H-4Kword 128		
3E0000H-1F0000H	1F0000H	32Kword 60		5E0000H-2F0000H	32Kword 94	7F0000H-4Kword 127		
3EFFFFFFH	1F0000H	32Kword 59		5D0000H-2E8000H	32Kword 93	7E0000H-32Kword 126		
3A0000H-1D0000H	1D7FFFH	32Kword 58		5C0000H-2E0000H	32Kword 92	7D0000H-32Kword 125		
3AFFFFFFH	1D7FFFH	32Kword 57		5B0000H-2D8000H	32Kword 91	7C0000H-32Kword 124		
390000H-1C8000H	1C8000H	32Kword 56		5BFFFFFFH	32Kword 90	7B0000H-32Kword 123		
39FFFFFFH	1C8000H	32Kword 55		5A0000H-2D0000H	32Kword 89	7A0000H-32Kword 122		
360000H-1B8000H	1B8000H	32Kword 54		5AFFFFFFH	32Kword 88	790000H-32Kword 121		
36FFFFFFH	1B8000H	32Kword 53		570000H-2B8000H	32Kword 87	780000H-32Kword 120		
340000H-1A0000H	1A0000H	32Kword 52		560000H-2B0000H	32Kword 86	770000H-32Kword 119		
34FFFFFFH	1A0000H	32Kword 51		550000H-2A8000H	32Kword 85	760000H-32Kword 118		
330000H-198000H	198000H	32Kword 50		540000H-2A0000H	32Kword 84	750000H-32Kword 117		
33FFFFFFH	198000H	32Kword 49		530000H-298000H	32Kword 83	740000H-32Kword 116		
300000H-180000H	180000H	32Kword 48		520000H-290000H	32Kword 82	730000H-32Kword 115		
30FFFFFFH	180000H	32Kword 47		510000H-288000H	32Kword 81	720000H-32Kword 114		
2F0000H-178000H	178000H	32Kword 46		500000H-280000H	32Kword 80	710000H-32Kword 113		
2FFFFFFFH	178000H	32Kword 45		4F0000H-278000H	32Kword 79	700000H-32Kword 112		
2C0000H-160000H	160000H	32Kword 44		4E0000H-270000H	32Kword 78	6F0000H-32Kword 111		
2CFFFFFFH	160000H	32Kword 43		4D0000H-268000H	32Kword 77	6E0000H-32Kword 110		
2B0000H-158000H	158000H	32Kword 42		4C0000H-260000H	32Kword 76	6D0000H-32Kword 109		
2BFFFFFFH	158000H	32Kword 41		4B0000H-258000H	32Kword 75	6C0000H-32Kword 108		
2A0000H-150000H	150000H	32Kword 40		4A0000H-250000H	32Kword 74	6B0000H-32Kword 107		
2AFFFFFH	150000H	32Kword 39		490000H-248000H	32Kword 73	6A0000H-32Kword 106		
290000H-148000H	148000H	32Kword 38		480000H-240000H	32Kword 72	6F0000H-32Kword 105		
29FFFFFFH	148000H	32Kword 37		470000H-238000H	32Kword 71	69FFFFFFH-32Kword 104		
280000H-140000H	140000H	32Kword 36		460000H-230000H	32Kword 70	67FFFFFFH-32Kword 103		
28FFFFFFH	140000H	32Kword 35		450000H-228000H	32Kword 69	66FFFFFFH-32Kword 102		
220000H-110000H	110000H	32Kword 34		440000H-220000H	32Kword 68	A21-A-1 A21-A0 (Byte Mode) (Word Mode)		
22FFFFFFH	110000H			43FFFFFFH		A21-A-1 A21-A0 (Byte Mode) (Word Mode)		

M5M29KB/T641AVP

**67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Bus Operation

Mode	Pins	CE#	OE#	WE#	RP#	DQ0-15*	RY/BY#
Read	Array	VIL	VIL	VIH	VIH	Data Output	$V_{OH(Hi-Z)}$
	Status Register	VIL	VIL	VIH	VIH	Status Register Data	X ²⁾
	Identifier Code	VIL	VIL	VIH	VIH	Identifier Code	$V_{OH(Hi-Z)}$
	Page	VIL	VIL	VIH	VIH	Data Output	$V_{OH(Hi-Z)}$
Output Disable		VIL	VIH	VIH	VIH	High-Z	X ²⁾
Write	Program	VIL	VIH	VIL	VIH	Command/Data in	X ²⁾
	Erase	VIL	VIH	VIL	VIH	Command	X ²⁾
	Others	VIL	VIH	VIL	VIH	Command	X ²⁾
Stand by		VIH	X ¹⁾	X ¹⁾	VIH	High-Z	X ²⁾
Deep Power Down		X ¹⁾	X ¹⁾	X ¹⁾	VIL	High-Z	$V_{OH(Hi-Z)}$

* In case of Byte(x8) organization, DQ8-DQ15 is ignored.

1) X can be VIH or VIL for control pins.

2) X at RY/BY# is V_{OL} or $V_{OH(Hi-Z)}$.

The RY/BY# is an open drain output pin and indicates status of the internal WSM. When low, it indicates that the WSM is busy performing an operation. A pull-up resistor of 10K-100K Ohms is required to allow the RY/BY# signal to transition high indicating a Ready WSM condition.

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**67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Software Command Definition**Command List (WP# =VIH or VIL)**

Command	1st Bus Cycle			2nd Bus Cycle			3rd-5th Bus Cycles		
	Mode	Address	Data ¹⁾ (DQ0-15)	Mode	Address		Data (DQ0-15)	Mode	Address
					A21-A18	A0			
Read Array	Write	X	FFH						
Page Read	Write	X	F3H	Read	SA ⁵⁾		RD0 ⁵⁾	Read	SA+i ⁶⁾
Device Identifier	Write	Bank ²⁾	90H	Read	Bank ²⁾	IA ³⁾	ID ³⁾		
Read Status Register	Write	Bank ²⁾	70H	Read	Bank ²⁾		SRD ⁴⁾		
Clear Status Register	Write	X	50H						
Suspend	Write	Bank ²⁾	B0H						
Resume	Write	Bank ²⁾	D0H						

1) In the case of Word mode(BYTE#=VIH), upper byte data (DQ15-DQ8) is ignored.

2) Bank=Bank address (Bank(I)-Bank(IV): A21-18)

3) IA=ID code address: A0=VIL (Manufacturer's code): A0=VIH (Device code), ID=ID code

4) SRD=Status Register Data

5) SA=A21-A2:1st Page Address, A1,A0:voluntary address / RD0=1st Page read data

6) SA+i: Page address(is equal to 1st Page Address of A21-A2), A1,A0: voluntary address / RDi: 2nd Page read data

Command List (WP# =VIH)

Command	1st Bus Cycle			2nd Bus Cycle			3rd-129th Bus Cycles(Word mode) 3rd-257th Bus Cycles(Byte mode)		
	Mode	Address	Data ¹⁾ (DQ0-15),(DQ0-7)	Mode	Address	Data (DQ0-15),(DQ0-7)	Mode	Address	Data (DQ0-15),(DQ0-7)
Word/Byte Program	Write	Bank	40H	Write	WA ²⁾	WD ²⁾			
Page Program	Write	Bank	41H	Write	WA0 ³⁾	WD0 ³⁾	Write	WAn ³⁾	WDn ³⁾
Page Buffer to Flash	Write	Bank	0EH	Write	WA ⁴⁾	D0H ¹⁾			
Block Erase/Confirm	Write	Bank	20H	Write	BA ⁵⁾	D0H ¹⁾			
Erase All Unlocked Blocks	Write	X	A7H	Write	X	D0H ¹⁾			
Clear Page Buffer	Write	X	55H	Write	X	D0H ¹⁾			
Single Data Load to Page Buffer	Write	Bank	74H	Write	WA	WD			
Flash to Page Buffer	Write	Bank	F1H	Write	RA ⁶⁾	D0H ¹⁾			

1) In the case of Word mode(BYTE#=VIH), upper byte data (DQ15-DQ8) is ignored.

2) WA=Write Address, WD=Write Data

3) WA0, WAn=Write Address, WD0, WDn=Write Data.

Word mode (BYTE#=VIH) : Write address and write data must be provided sequentially from 00H to 7FH for A6-A0. Page size is 128 words (128-word x 16-bit), and also A21-A7 (block address, page address) must be valid.

Byte mode (BYTE#=VIL) : Write address and write data must be provided sequentially from 00H to FFH for A6-A-1. Page size is 256 Bytes (256-byte x 8-bit), and also A21-A7 (block address, page address) must be valid.

4) WA=Write Address: A21-A7 (block address, page address) must be valid.

5) BA=Block Address : A21-A12[Bank(I)], A21-A15 [Bank(II), Bank(III), Bank(IV)]

6) RA=Read Address: A21-A7 (block address, page address) must be valid.

M5M29KB/T641AVP

**67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Software Command Definition Command List (WP#=VIL)

Software lock release operation needs following consecutive 7bus cycles. Moreover, additional 127(255) bus cycles are needed for page program operation.

Setup Command for Software Lock Release	1st Bus Cycle			2nd Bus Cycle			3rd Bus Cycle		
	Mode	Address	Data ¹⁾ (DQ0-15/DQ0-7)	Mode	Address	Data ¹⁾ (DQ0-15/DQ0-7)	Mode	Address	Data ¹⁾ (DQ0-15/DQ0-7)
Word/Byte Program	Write	Bank	60H	Write	Bank	Block ⁶⁾	Write	Bank	ACH
Page Program	Write	Bank	60H	Write	Bank	Block ⁶⁾	Write	Bank	ACH
Page Buffer to Flash	Write	Bank	60H	Write	Bank	Block ⁶⁾	Write	Bank	ACH
Block Erase/Confirm	Write	Bank	60H	Write	Bank	Block ⁶⁾	Write	Bank	ACH
Clear Page Buffer	Write	Bank	60H	Write	Bank	Block ⁶⁾	Write	Bank	ACH
Single Data Load to Page Buffer	Write	Bank	60H	Write	Bank	Block ⁶⁾	Write	Bank	ACH
Flash to Page Buffer	Write	Bank	60H	Write	Bank	Block ⁶⁾	Write	Bank	ACH

Setup Command for Software Lock Release	4th Bus Cycle			5th Bus Cycle		
	Mode	Address	Data ¹⁾ (DQ0-15/DQ0-7)	Mode	Address	Data ¹⁾ (DQ0-15/DQ0-7)
Word/Byte Program	Write	Bank	Block# ⁶⁾	Write	Bank	7BH
Page Program	Write	Bank	Block# ⁶⁾	Write	Bank	7BH
Page Buffer to Flash	Write	Bank	Block# ⁶⁾	Write	Bank	7BH
Block Erase/Confirm	Write	Bank	Block# ⁶⁾	Write	Bank	7BH
Clear Page Buffer	Write	Bank	Block# ⁶⁾	Write	Bank	7BH
Single Data Load to Page Buffer	Write	Bank	Block# ⁶⁾	Write	Bank	7BH
Flash to Page Buffer	Write	Bank	Block# ⁶⁾	Write	Bank	7BH

Setup Command for Program or Erase Operations	6th Bus Cycle			7th Bus Cycle			8th-134th Bus Cycles(Word mode) 8th-262th Bus Cycles(Byte mode)		
	Mode	Address	Data ¹⁾ (DQ0-15/DQ0-7)	Mode	Address	Data (DQ0-15/DQ0-7)	Mode	Address	Data (DQ0-15/DQ0-7)
Word/Byte Program	Write	Bank	40H	Write	WA ²⁾	WD ²⁾			
Page Program	Write	Bank	41H	Write	WA0 ³⁾	WD0 ³⁾	Write	WAn ³⁾	WDn ³⁾
Page Buffer to Flash	Write	Bank	0EH	Write	WA ⁴⁾	D0H ¹⁾			
Block Erase/Confirm	Write	Bank	20H	Write	BA ⁵⁾	D0H ¹⁾			
Clear Page Buffer	Write	X	55H	Write	X	D0H ¹⁾			
Single Data Load to Page Buffer	Write	Bank	74H	Write	WA	WD			
Flash to Page Buffer	Write	Bank	F1H	Write	RA ⁷⁾	D0H ¹⁾			

1) In the case of word mode(BYTE#=VIH) upper byte data (DQ15-DQ8) is ignored.

2) WA=Write Address, WD=Write Data

3) WA0, WAn=Write Address, WD0, WDn=Write Data. Write address and write data must be provided sequentially from 00H to 7FH for A6-A0(word mode) and from 00H to FFH for A6-A-1(byte mode), respectively.

Page size is 128 words (128-word x 16-bit/ word mode) or Page size is 256 bytes (256-word x 8-bit/ byte mode), and also A21-A7 (block address, page address) must be valid.

4) WA=Write Address: A21-A7 (block address, page address) must be valid.

5) BA=Block Address : A21-A12[Bank(I)], A21-A15 [Bank(II), Bank(III), Bank(IV)]

6) Block=Block Address: A21-A15, Block#=A21#-A15#

Address	DQ7	DQ6	DQ5	DQ4	DQ3	DQ2	DQ1	DQ0
Block	fixed 0	A21	A20	A19	A18	A17	A16	A15
Block#	fixed 0	A21#	A20#	A19#	A18#	A17#	A16#	A15#

7) RA=Read Address: A21-A7 (block address, page address) must be valid.

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**67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Block Locking

RP#	WP#	Write Protection Provided				Notes	
		Bank(I)		Bank(II)	Bank(III)		
		Boot	Parameter/Main	Main	Main		
VIL	X	Locked	Locked	Locked	Locked	Locked	Deep Power Down Mode
VIH	VIL	Locked	Locked	Locked	Locked	Locked	All Blocks Locked(Valid to operate Software Lock Release)
	VIH	Unlocked	Unlocked	Unlocked	Unlocked	Unlocked	All Blocks Unlocked

WP# pin must not be switched during performing Read / Write operations or WSM busy (WSMS=0).

Status Register

Symbol (I/O Pin)	Status	Definition	
		"1"	"0"
S.R. 7 (DQ7)	Write State Machine Status	Ready	Busy
S.R. 6 (DQ6)	Suspend Status	Suspended	Operation in Progress/Completed
S.R. 5 (DQ5)	Erase Status	Error	Successful
S.R. 4 (DQ4)	Program Status	Error	Successful
S.R. 3 (DQ3)	Block Status after Erase	Error	Successful
S.R. 2 (DQ2)	Reserved	-	-
S.R. 1 (DQ1)	Reserved	-	-
S.R. 0 (DQ0)	Reserved	-	-

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**67,108,864-BIT (8,388,608-WORD BY 8-BIT / 4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Device ID Code

Pins Code	A0	DQ7	DQ6	DQ5	DQ4	DQ3	DQ2	DQ1	DQ0	Hex. Data
Manufacturer Code	VIL	"0"	"0"	"0"	"1"	"1"	"1"	"0"	"0"	1CH
Device Code (Top Boot)	VIH	"1"	"0"	"1"	"1"	"1"	"0"	"0"	"0"	B8H
Device Code (Bottom Boot)	VIH	"1"	"0"	"1"	"1"	"1"	"0"	"0"	"1"	B9H

The output of upper byte data (DQ15-DQ8) is "0H".

Absolute Maximum Ratings

Symbol	Parameter	Conditions	Min.	Max.	Units
VCC	VCC Voltage	With Respect to GND	-0.2	4.6	V
VI1	All Input or Output Voltage ¹⁾		-0.6	4.6	V
Ta	Ambient Temperature		-40	85	°C
Tbs	Temperature under Bias		-50	95	°C
Tstg	Storage Temperature		-65	125	°C
Iout	Output Short Circuit Current		100		mA

1) Minimum DC voltage is -0.6V on input / output pins. During transitions, the level may undershoot to -2.0V for periods <20ns. Maximum DC voltage on input / output pins is VCC+0.5V which, during transitions, may overshoot to VCC+1.5V for periods <20ns.

DC electrical characteristics (Ta= -40 ~85 °C and Flash VCC=3.0V~3.6V, unless otherwise noted)

Symbol	Parameter	Test Conditions	Limits			Units
			Min.	Typ. ¹⁾	Max.	
ILI	Input Leakage Current	0V ≤ VIN ≤ VCC	-1		1	μA
ILO	Output Leakage Current	0V ≤ VOUT ≤ VCC	-10		10	μA
ISB2	VCC Stand by Current	VCC= 3.6V, VIN= GND/VCC, F-CE#= F-RP#= F-WP#= VCC±0.3V		0.1	6	μA
ISB3		VCC= 3.6V, VIN= VIL/VIH, F-RP#= VIL		5	25	μA
ISB4	VCC Deep Power Down Current	VCC= 3.6V, VIN= GND or VCC, F-RP#= GND± 0.3V		0.1	6	μA
ICC1	VCC Read Current for Word	Vcc = 3.6V, VIN = VIL/VIH, F-RP# = OE# = VIH,	5MHz		20	mA
		F-CE# =VIL, Iout = 0mA	1MHz		4	mA
ICC1P	VCC Page Read Current	Vcc = 3.6V, VIN = VIL/VIH, F-RP# = OE# = VIH, F-CE# =VIL, Iout = 0mA	5MHz		5	mA
ICC2	VCC Write Current for Word	Vcc = 3.6V, VIN = VIL/VIH, F-RP# = OE# = VIH, F-CE# = WE# = VIL			15	mA
ICC3	VCC Program Current	VCC = 3.6V, VIN = VIL/VIH, F-CE#= F-RP#= F-WP#= VIH			35	mA
ICC4	VCC Erase Current	VCC = 3.6V, VIN = VIL/VIH, F-CE#= F-RP#= F-WP#= VIH			35	mA
ICC5	VCC Suspend Current	VCC = 3.6V, VIN = VIL/VIH, F-CE#= F-RP#= F-WP#= VIH			200	μA
VIL	Input Low Voltage		-0.5		0.4	V
VIH	Input High Voltage		2.4		VCC+0.5	V
VOL	Output Low Voltage	IOL = 4.0mA			0.45	V
VOH1	Output High Voltage	IOH = -2.0mA	0.85xVCC			V
VOH2		IOH = -100uA	VCC-0.4			V
VLKO	Low VCC Lock Out Voltage ²⁾		1.5		2.2	V

All currents are in RMS unless otherwise noted.

1) Typical values at Flash VCC=3.3V, Ta=25 °C.

2) To protect against initiation of write cycle during Flash VCC power up / down, a write cycle is locked out for Flash VCC less than VLKO.

If Flash VCC is less than VLKO, Write State Machine is reset to read mode. When the Write State Machine is in Busy state, if Flash VCC is less than VLKO, the alteration of memory contents may occur.

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**67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

AC electrical characteristics (Ta=-40 ~85 °C and Flash VCC=3.0V~3.6V, unless otherwise noted)

Read Only Mode

Symbol	Parameter	Limits			Units	
		Flash VCC=3.0-3.6V				
		Min.	Typ.	Max.		
tRC	tAVAV	Read Cycle Time	70		ns	
ta(AD)	tAVQV	Address Access Time			70 ns	
ta(CE)	tELQV	Chip Enable Access Time			70 ns	
ta(OE)	tGLQV	Output Enable Access Time			30 ns	
ta(PAD)	tPAVQV	Page Read Access Time			25 ns	
tCEPH		CE# "H"Pulse width	30		ns	
tCLZ	tELQX	Chip Enable to Output in Low-Z	0		ns	
tDF(CE)	tEHQZ	Chip Enable High to Output in High-Z			25 ns	
tOLZ	tGLQX	Output Enable to Output in Low-Z	0		ns	
tDF(OE)	tGHQZ	Output Enable to High to Output in High-Z			25 ns	
tPHZ	tPLQZ	RP# Low to Output High-Z			150 ns	
ta(BYTE)	tFL/HQV	BYTE# access time			70 ns	
tBHZ	tFLQZ	BYTE# low to output high-Z			25 ns	
tOH	tOH	Output Hold from CE#, OE# and Addresses	0		ns	
tBCD	tELFL/H	CE# low to BYTE# high or low			5 ns	
tBAD	tAVFL/H	Address to BYTE# high or low			5 ns	
tOEH	tWHGL	OE# Hold from WE# High	10		ns	
tPS	tPHEL	RP# Recovery to CE# Low	150		ns	

-Timing measurements are made under AC waveforms for read operations.

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**67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

AC electrical characteristics (Ta=-40 ~85 °C and Flash VCC=3.0V~3.6V, unless otherwise noted)**Read / Write Mode (WE# control)**

Symbol	Parameter	Limits			Units	
		Flash VCC=3.0-3.6V		Min.	Typ.	Max.
tWC	tAVAV	Write Cycle Time	70			ns
tAS	tAVWH	Address Setup Time	35			ns
tAH	tWHAX	Address Hold Time	0			ns
tDS	tDVWH	Data Setup Time	35			ns
tDH	tWHDX	Data Hold Time	0			ns
tOEH	tWHGL	OE# Hold from WE# High	10			ns
tCS	tELWL	Chip Enable Setup Time	0			ns
tCH	tWHEH	Chip Enable Hold Time	0			ns
tWP	tWLWH	Write Pulse Width	35			ns
tWPH	tWHLW	Write Pulse Width High	30			ns
tBS	tFL/HWH	Byte enable high or low set-up time	35			ns
tBH	tWHFL/H	Byte enable high or low hold time	70			ns
tGHWL	tGHWL	OE# Hold to WE# Low	0			ns
tBLS	tPHHWH	Block Lock Setup to Write Enable High	70			ns
tBLH	tQVPH	Block Lock Hold from Valid SRD	0			ns
tDAP	tWHRH1	Duration of Auto Program Operation(Word Mode)		30	300	μs
tDAP	tWHRH1	Duration of Auto Program Operation(Byte Mode)		30	300	μs
tDAP	tWHRH1	Duration of Auto Program Operation(Page Mode)		4	80	ms
tDAE	tWHRH2	Duration of Auto Block Erase Operation		150	600	ms
tWHRL	tWHRL	Delay Time During Internal Operation			70	ns
tPS	tPHWL	RP# Recovery to CE# Low	150			ns

-Read timing parameters during command write operations mode are the same as during read only operation mode.

-Typical values at Flash VCC=3.3V and Ta=25 °C.

Read / Write Mode (CE# control)

Symbol	Parameter	Limits			Units	
		Flash VCC=3.0-3.6V		Min.	Typ.	Max.
tWC	tAVAV	Write Cycle Time	70			ns
tAS	tAVEH	Address Setup Time	35			ns
tAH	tEHAX	Address Hold Time	0			ns
tDS	tDVEH	Data Setup Time	35			ns
tDH	tEHDX	Data Hold Time	0			ns
tOEH	tEHGL	OE# Hold from CE# High	10			ns
tWS	tWLEL	Write Enable Setup Time	0			ns
tWH	tEHWL	Write Enable Hold Time	0			ns
tCEP	tELEH	CE# Pulse Width	35			ns
tCEPH	tEHEL	CE#"H" Pulse Width	30			ns
tBS	tFL/HEH	Byte enable high or low set-up time	35			ns
tBH	tEHFL/H	Byte enable high or low hold time	70			ns
tGHEL	tGHEL	OE# Hold to CE# Low	0			ns
tBLS	tPHHEH	Block Lock Setup to Write Enable High	70			ns
tBLH	tQVPH	Block Lock Hold from Valid SRD	0			ns
tDAP	tEHRH1	Duration of Auto Program Operation(Word Mode)		30	300	μs
tDAP	tEHRH1	Duration of Auto Program Operation(Byte Mode)		30	300	μs
tDAP	tEHRH1	Duration of Auto Program Operation(Page Mode)		4	80	ms
tDAE	tEHRH2	Duration of Auto Block Erase Operation		150	600	ms
tEHRL	tEHRL	Delay Time During Internal Operation			70	ns
tPS	tPHEL	RP# Recovery to CE# Low	150			ns

-Timing measurements are made under AC waveforms for read operations.

-Typical values at Flash VCC=3.3V and Ta=25 °C.

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**67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Program / Erase Time

Parameter	Min.	Typ.	Max.	Unit
Block Erase Time		150	600	ms
Main Block Write Time		1	4	sec
Page Write Time		4	80	ms
Flash to Page Buffer Time		100	150	μs

Program Suspend / Erase Suspend Time

Parameter	Min.	Typ.	Max.	Unit
Program Susupend Time			15	μs
Erase Susupend Time			15	μs

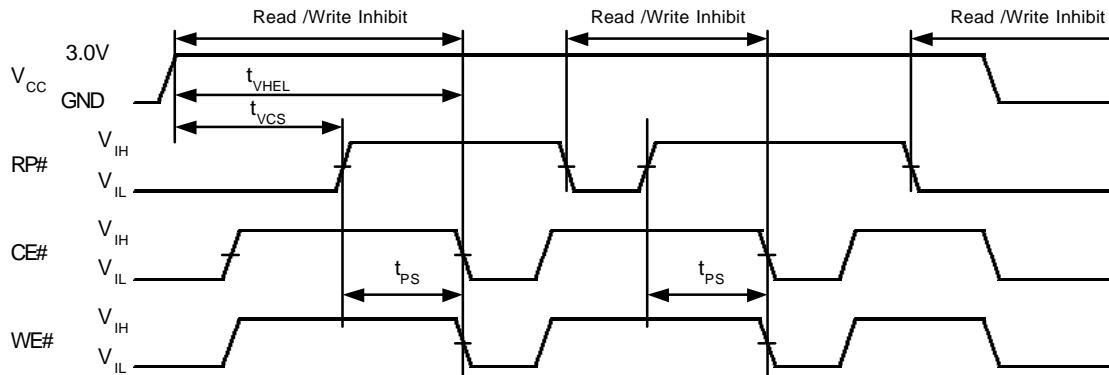
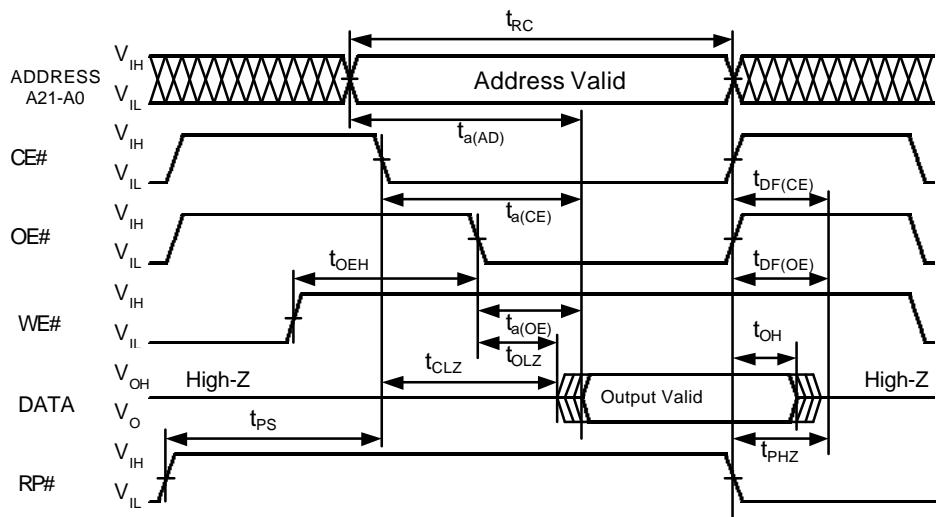
Flash VCC Power Up / Down Timing

symbol	Parameter	Min.	Typ.	Max.	Unit
tVCS	F-RP#=VIH Setup Time from Flash VCC min	2			μs
tVHEL	F-CE#=VIL Setup Time from Flash VCC min.	60			μs

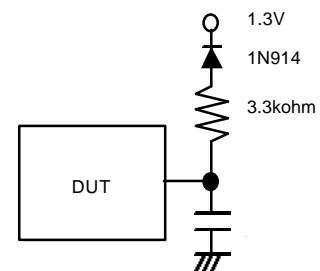
During power up / down, by the noise pulses on control pins, the device has possibility of accidental erase or programming. The device must be protected against initiation of write cycle for memory contents during power up / down. The delay time of min. 60 μsec is always required before read operation or write operation is initiated from the time Flash VCC reaches Flash VCC min. during power up /down. By holding RP#=VIL, the contents of memory is protected during Flash VCC power up / down. During power up, RP# must be held VIL for min. 2μs from the time Flash VCC reaches Flash VCC min.. During power down, RP# must be held VIL until Flash VCC reaches GND. RP# doesn't have latch mode, therefore RP# must be held VIH during read operation or erase / program operation.

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**67,108,864-BIT (8,388,608-WORD BY 8-BIT / 4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Flash VCC Power up / down Timing**AC Waveforms for Read Operation and Test Conditions****Test Conditions
for AC Characteristics**

Input Voltage : $V_{IL}=0V$, $V_{IH}=\text{Flash Vcc}$
Input Rise and Fall Times : $\leq 5\text{ns}$
Reference Voltage
at timing measurement : (Flash Vcc)/2
Output Load : 1 TTL gate +
 $CL(30\text{pF})$
or

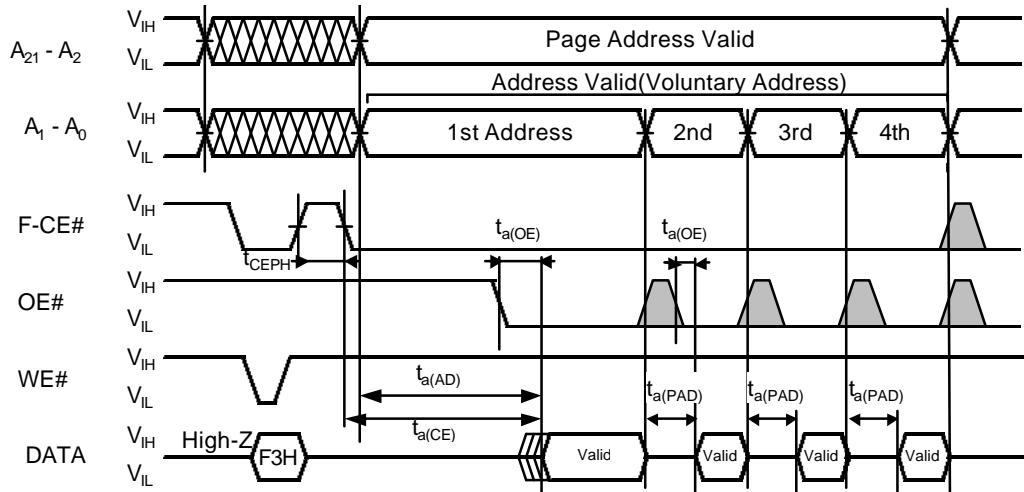


- After inputting Read Array FFH, it is necessary to make F-CE# "H" pulse more than 30ns (t_{CEPH}).

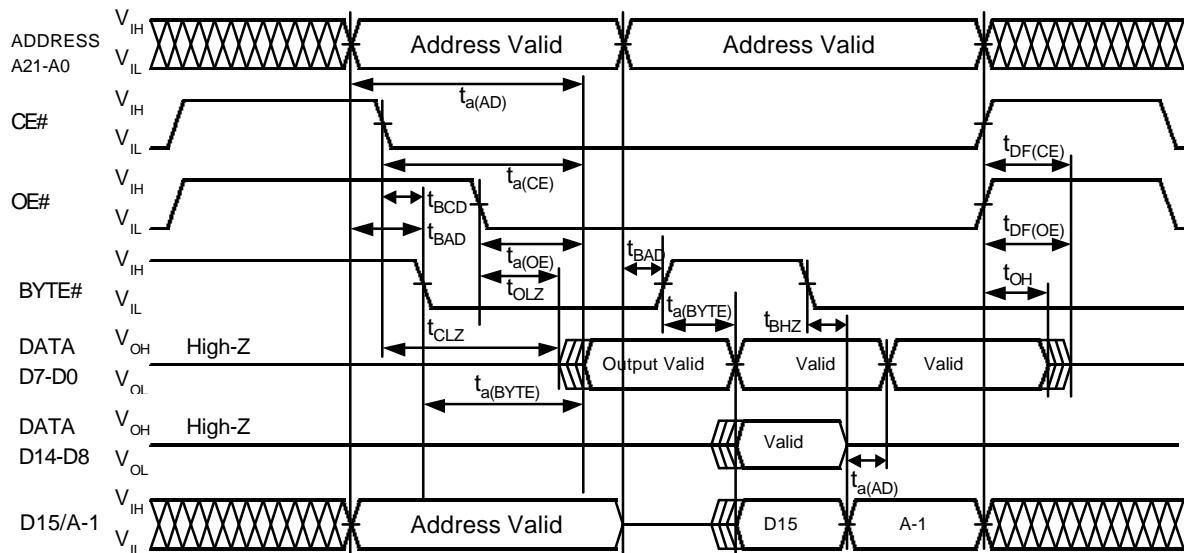
And after inputting Read Array Command FFH, it is also necessary to keep 30ns to recover before starting read after WE# rises "H" in case of changing address(es) and F-CE#=“L”.

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**67,108,864-BIT (8,388,608-WORD BY 8-BIT / 4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

AC waveforms for Page Read Operation

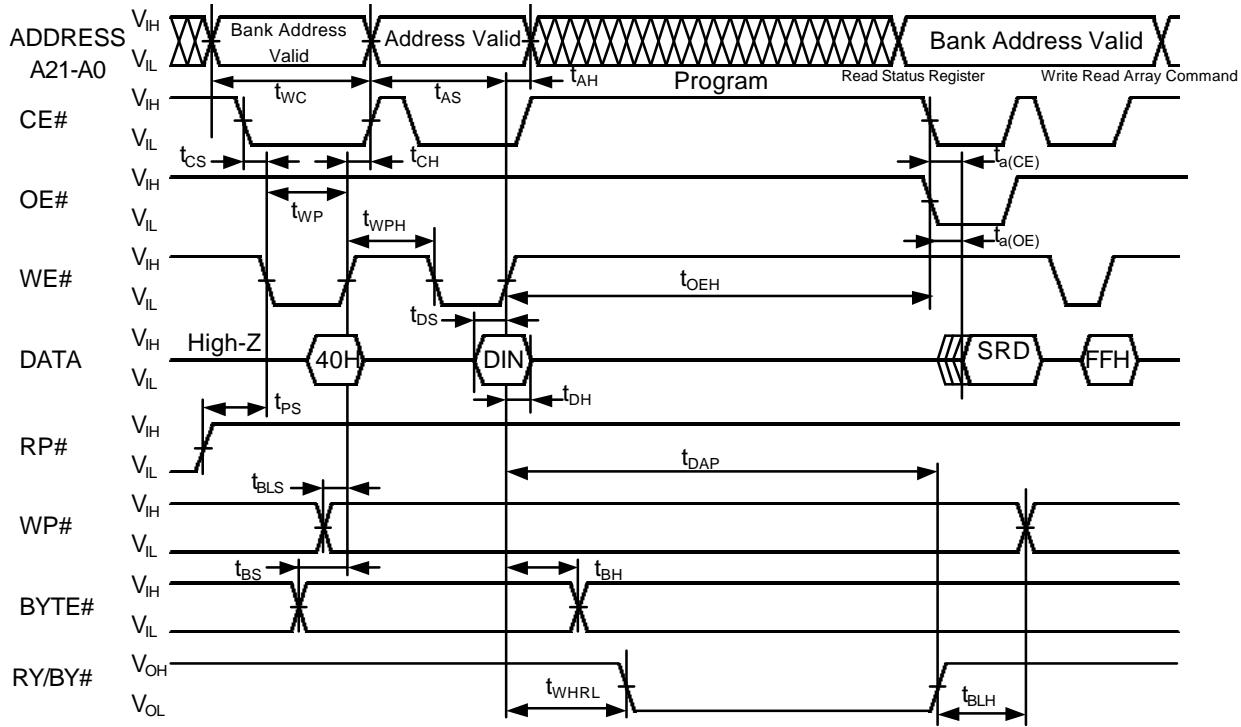
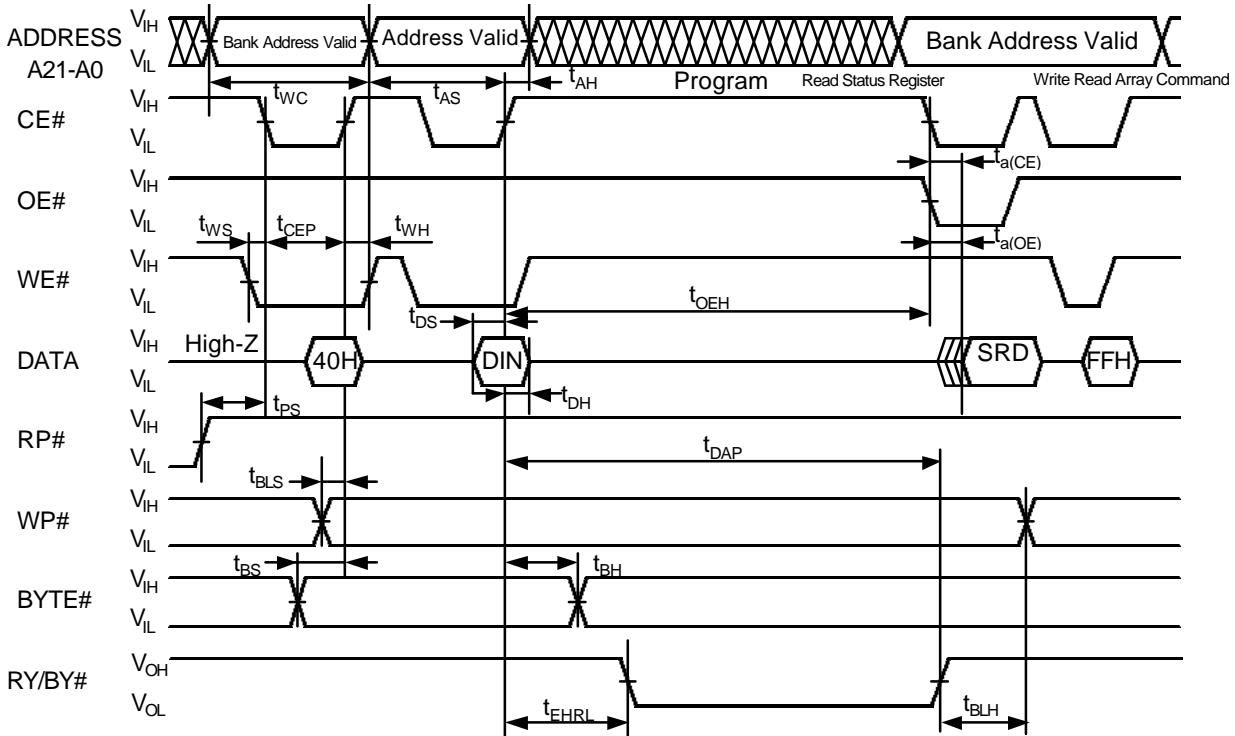
- After inputting Page Read Command F3H, it is necessary to make F-CE# "H" pulse more than 30ns (tCPEH). And after inputting Page Read Command F3H, it is also necessary to keep 30ns to recover before starting read after WE# rises "H" in case of changing address(es) and F-CE#=“L”.
- Once Page Read mode is valid, the mode is kept until F-RP# is set to VIL or the chip is powered off.

Word/Byte AC Waveforms for Read Operation

When BYTE# = VIH, CE# = OE# = VIL, D15/A-1 is output status. At this time, input signal must not be applied.

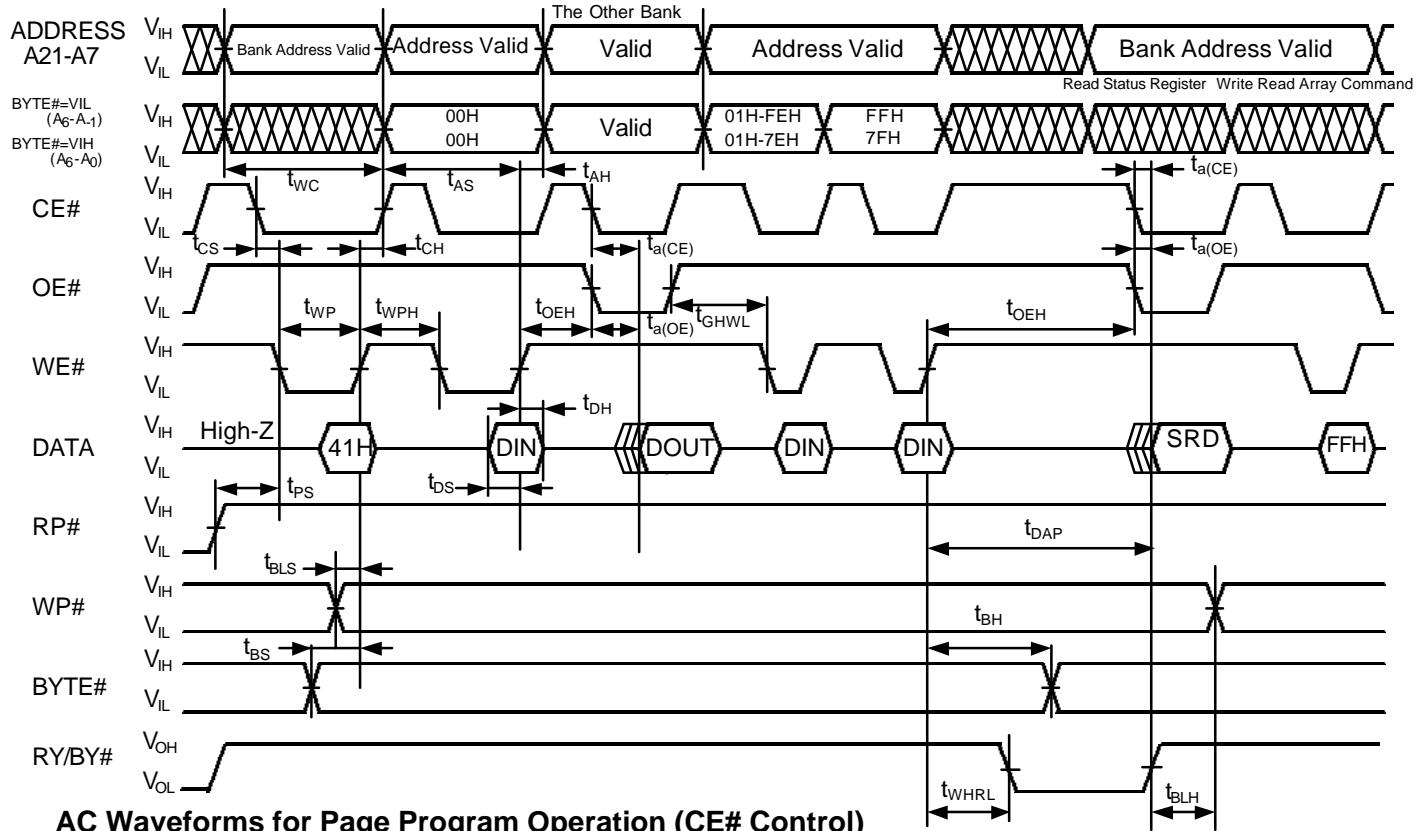
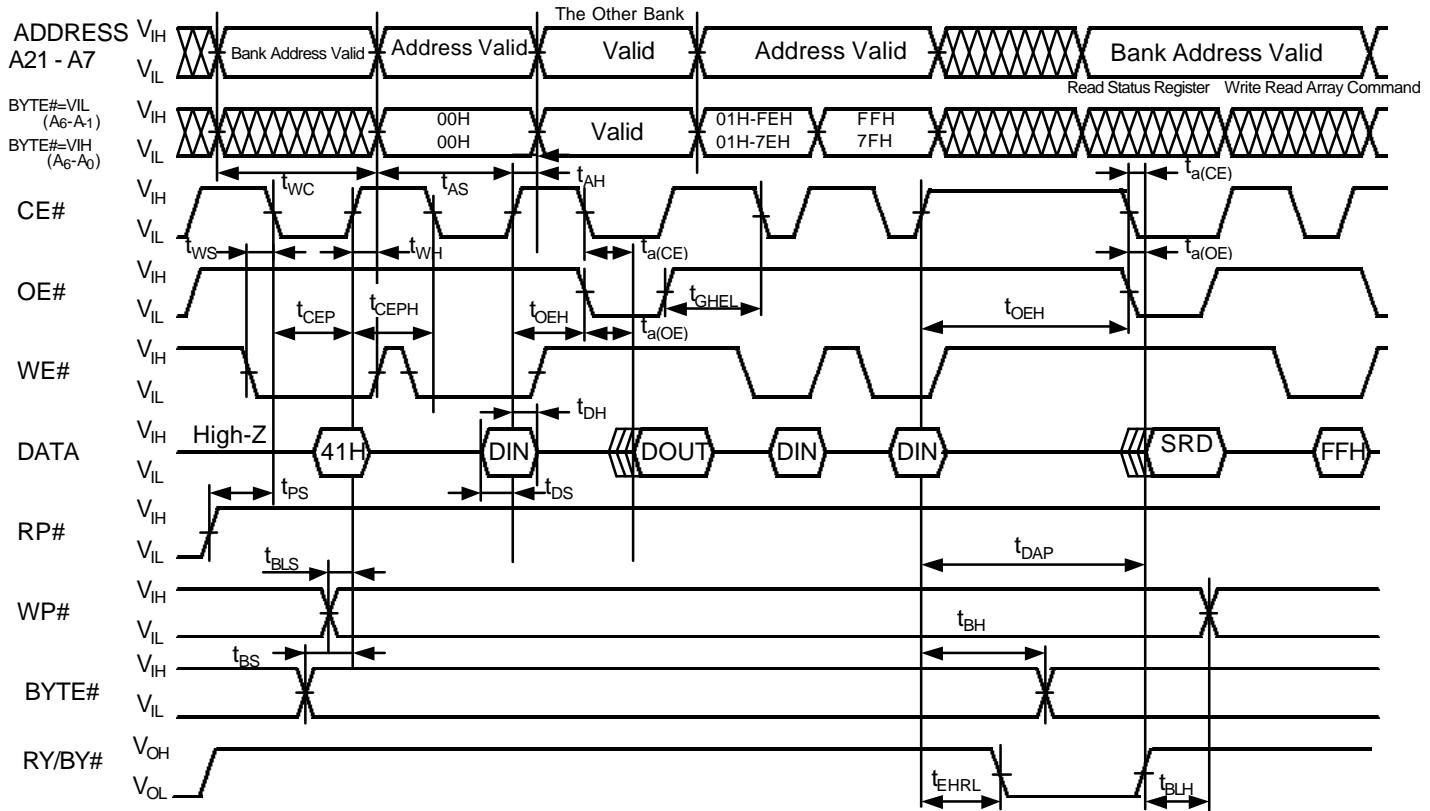
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67,108,864-BIT (8,388,608-WORD BY 8-BIT / 4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY

AC Waveforms for Word/Byte Program Operation (WE# Control)**AC Waveforms for Word/Byte Program Operation (CE# Control)**

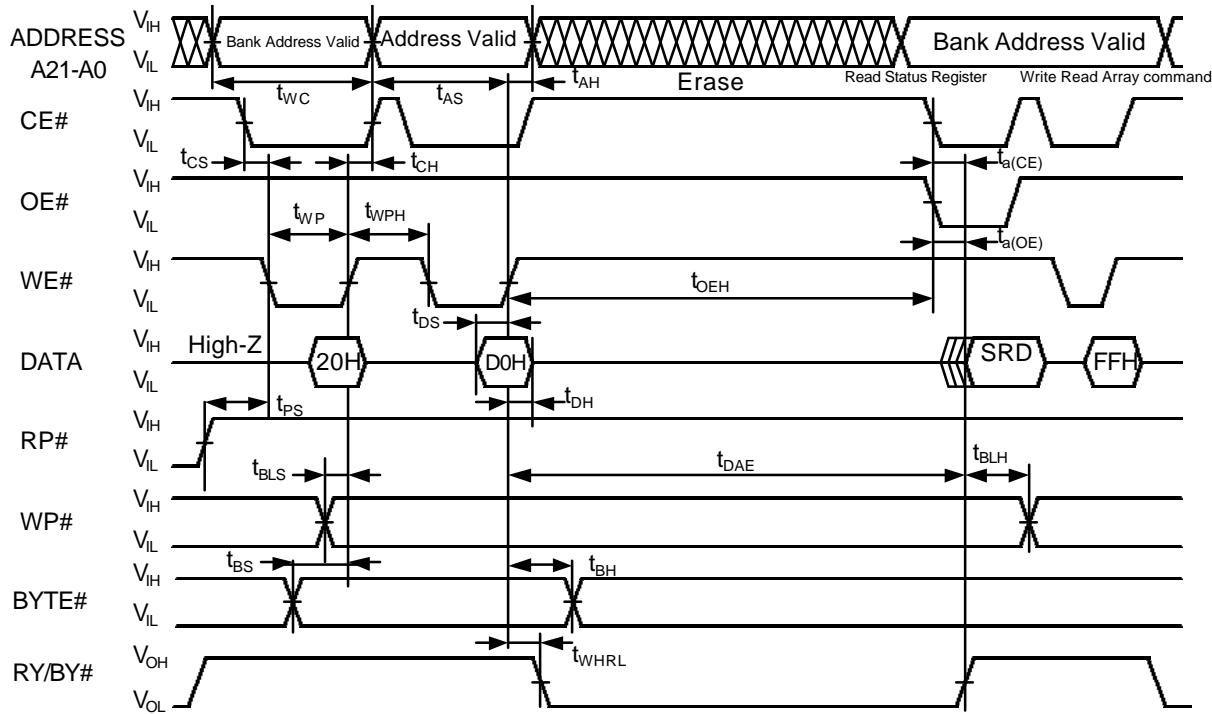
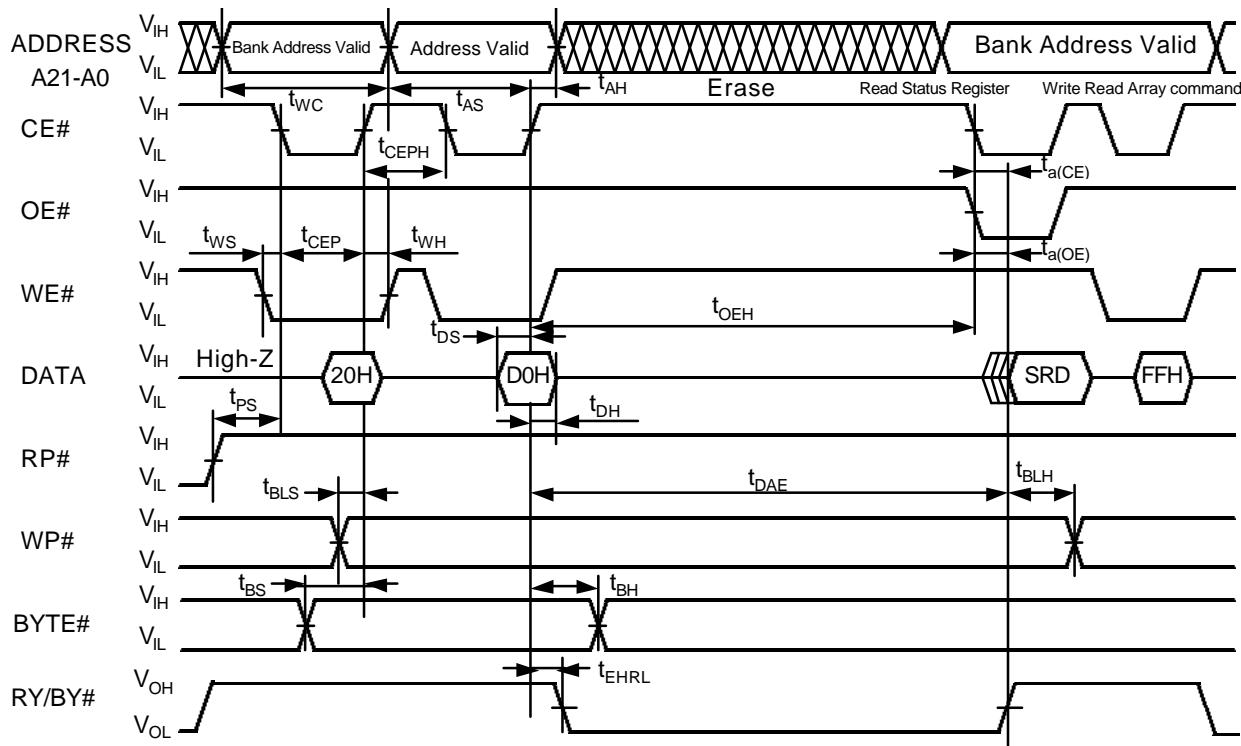
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67,108,864-BIT (8,388,608-WORD BY 8-BIT / 4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY

AC Waveforms for Page Program Operation (WE# Control)**AC Waveforms for Page Program Operation (CE# Control)**

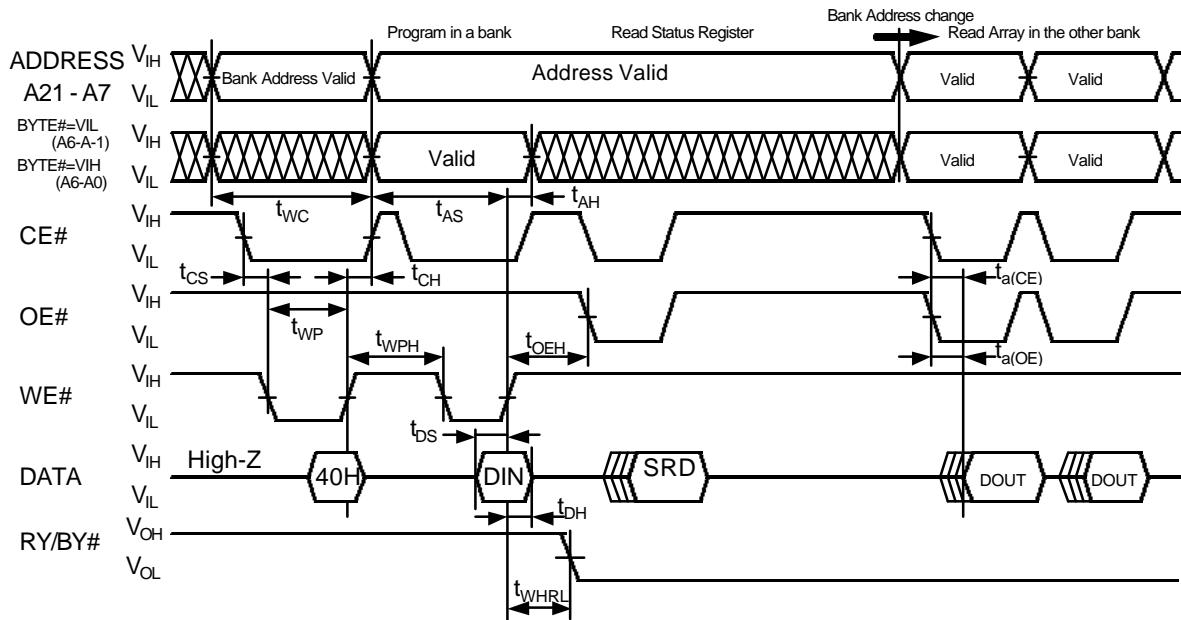
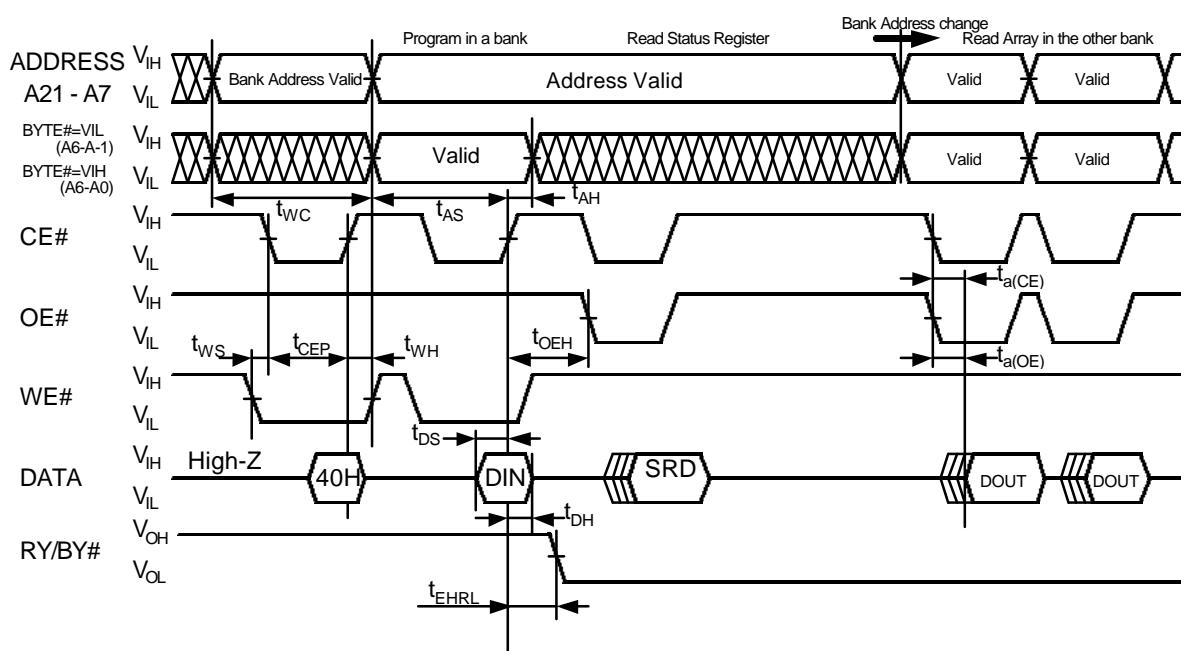
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**67,108,864-BIT (8,388,608-WORD BY 8-BIT / 4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

AC Waveforms for Erase Operation (WE# Control)**AC Waveforms for Erase Operation (CE# Control)**

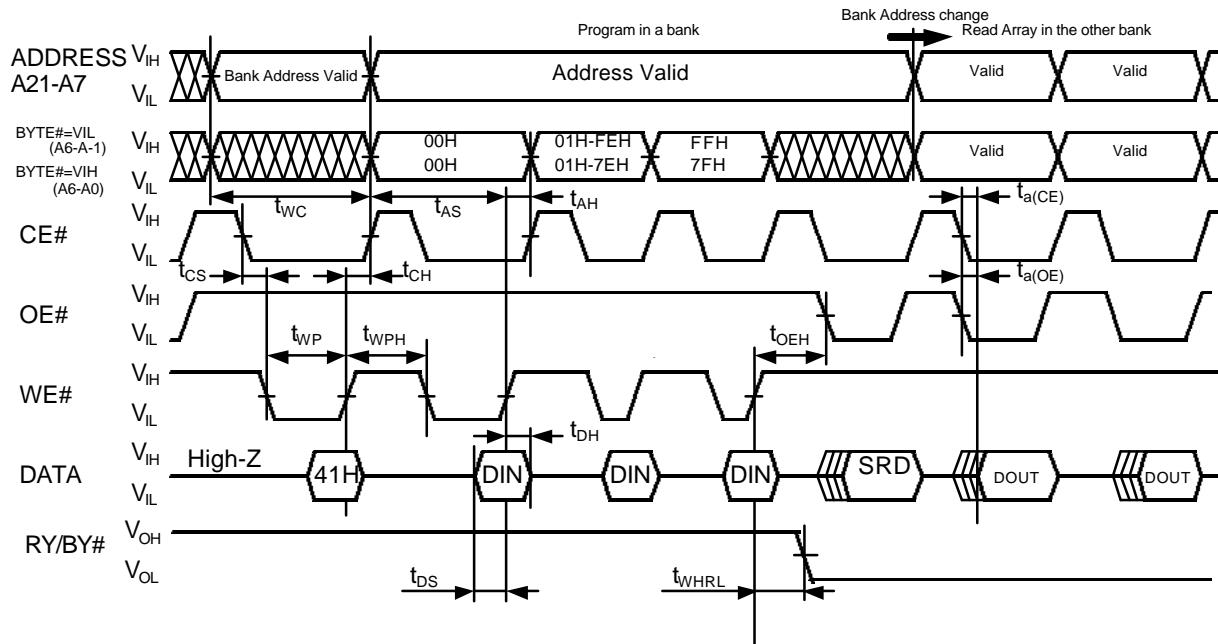
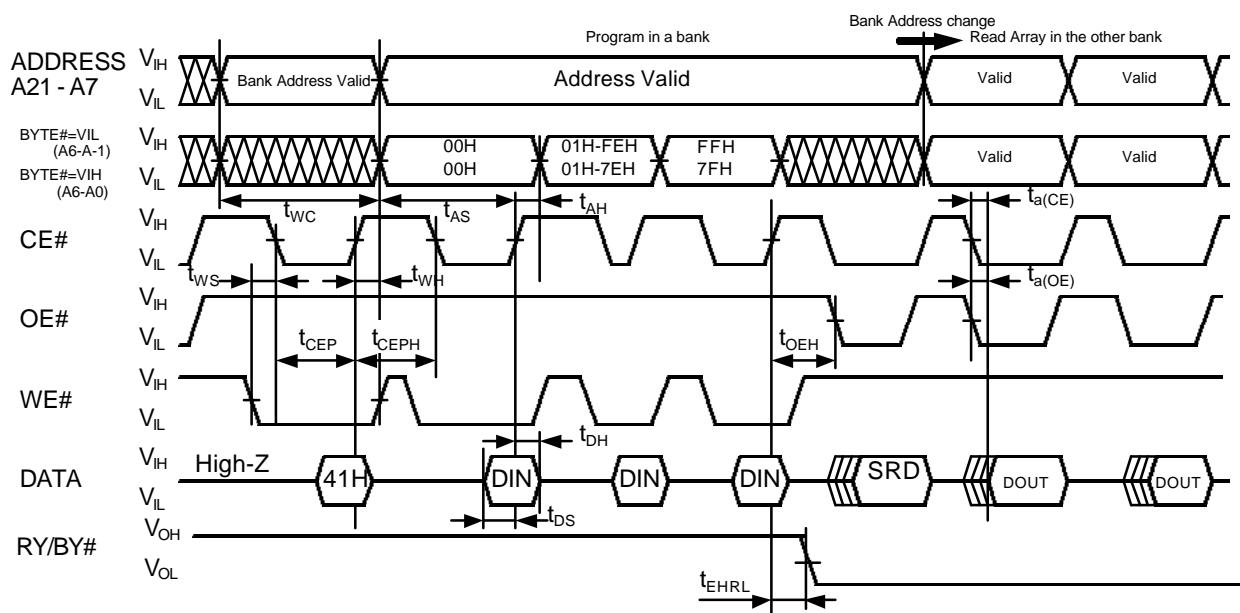
M5M29KB/T641AVP

**67,108,864-BIT (8,388,608-WORD BY 8-BIT / 4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

AC Waveforms for Word/Byte Program Operation with BGO (WE# Control)**AC Waveforms for Word/Byte Program Operation with BGO (CE# Control)**

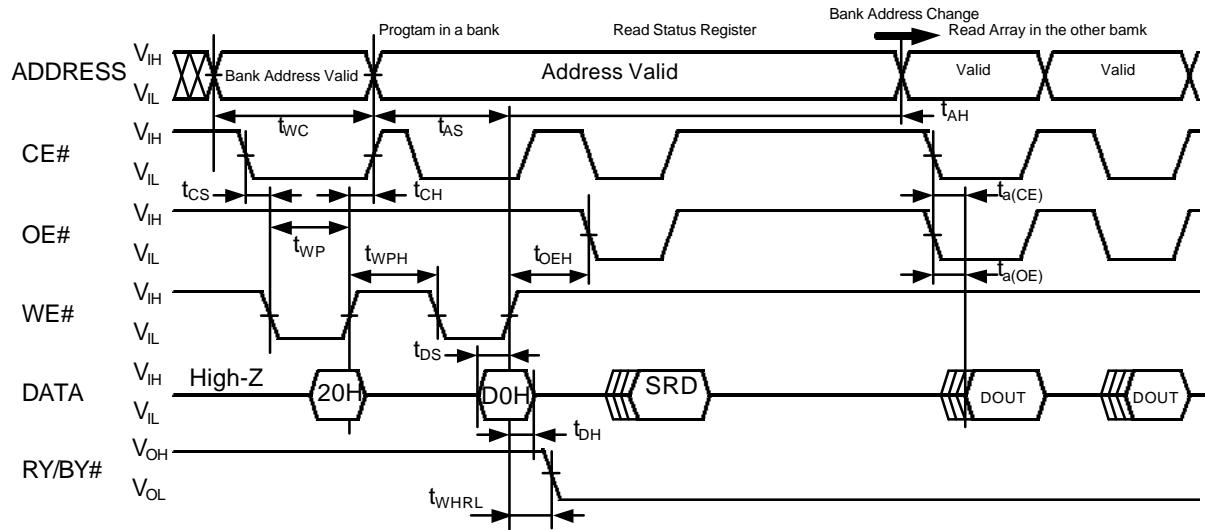
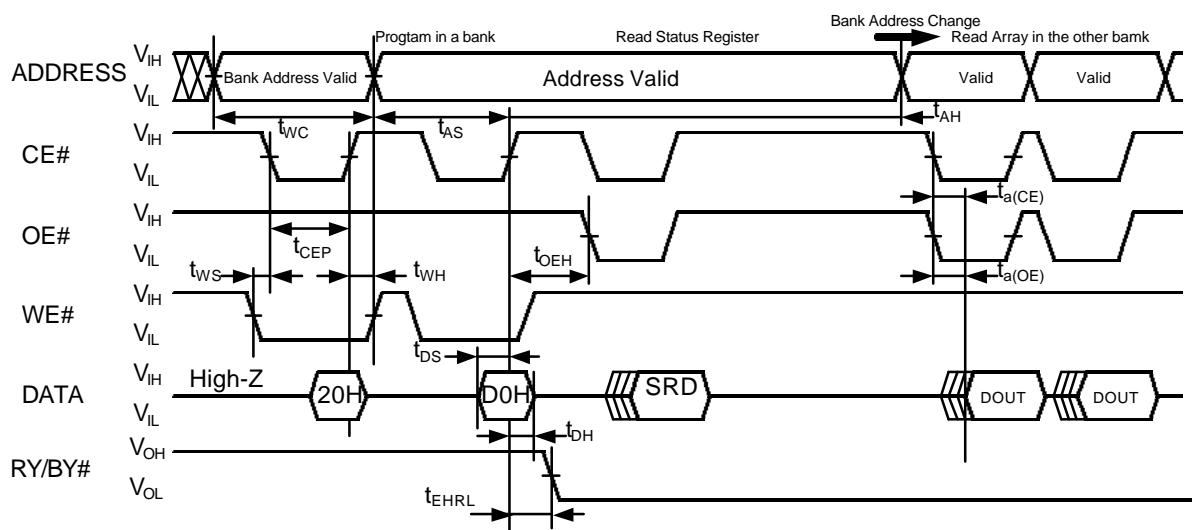
M5M29KB/T641AVP

**67,108,864-BIT (8,388,608-WORD BY 8-BIT / 4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

AC Waveforms for Page Program Operation with BGO (WE# Control)**AC Waveforms for Page Program Operation with BGO (CE# Control)**

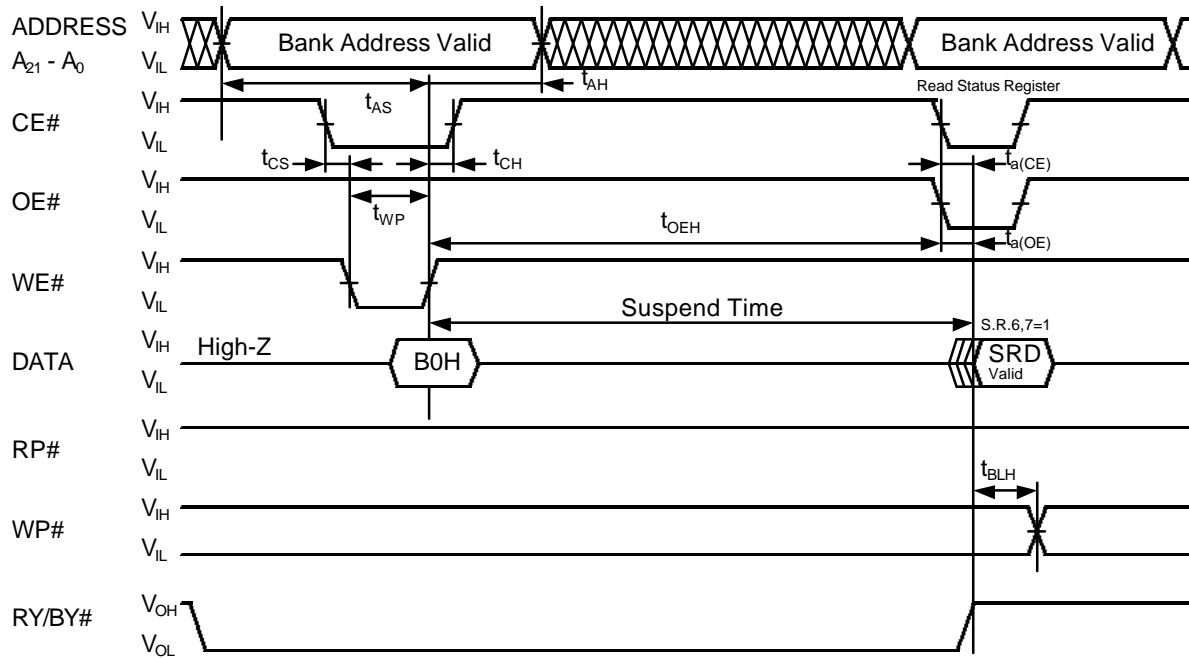
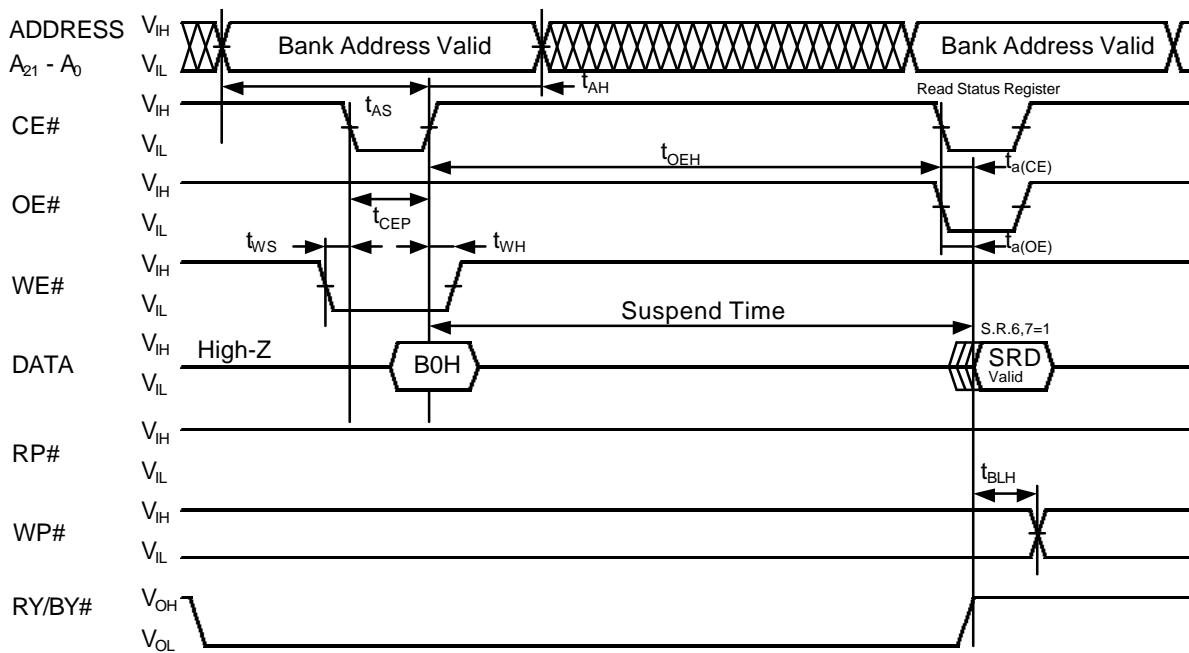
M5M29KB/T641AVP

**67,108,864-BIT (8,388,608-WORD BY 8-BIT / 4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

AC Waveforms for Erase Operation with BGO (WE# Control)**AC Waveforms for Erase Operation with BGO (CE# Control)**

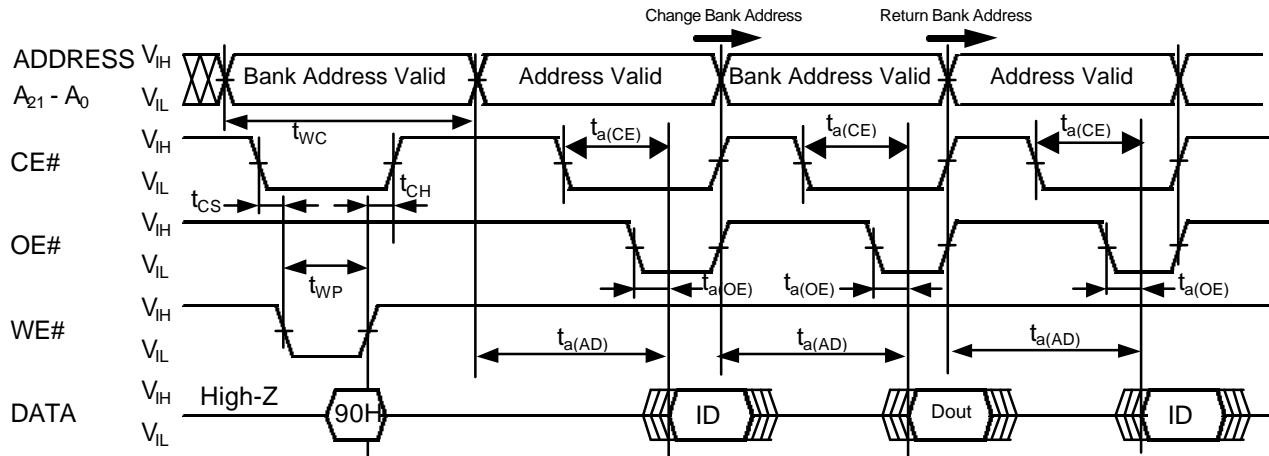
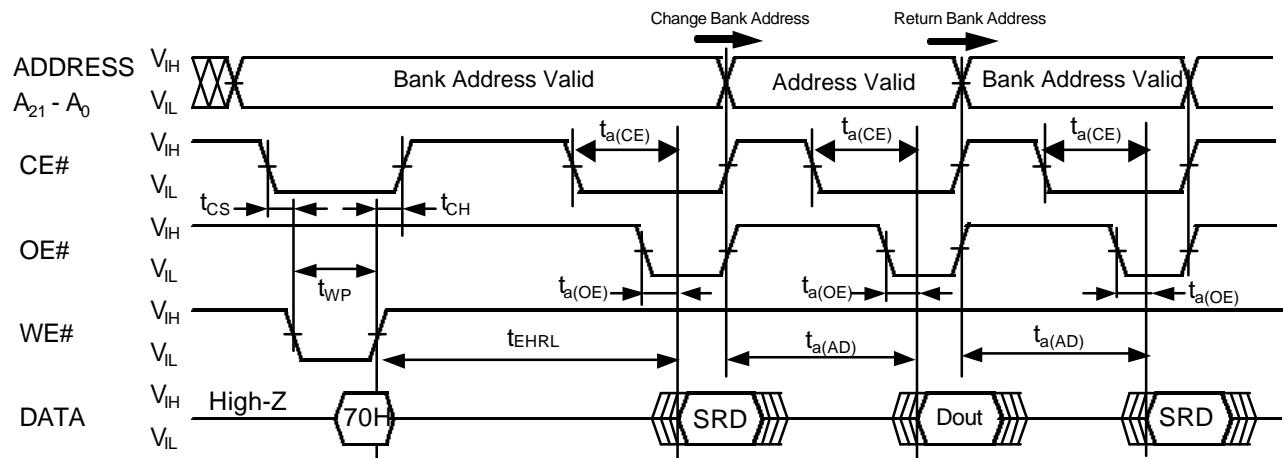
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**67,108,864-BIT (8,388,608-WORD BY 8-BIT / 4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

AC Waveforms for Suspend Operation (WE# Control)**AC Waveforms for Suspend Operation (CE# Control)**

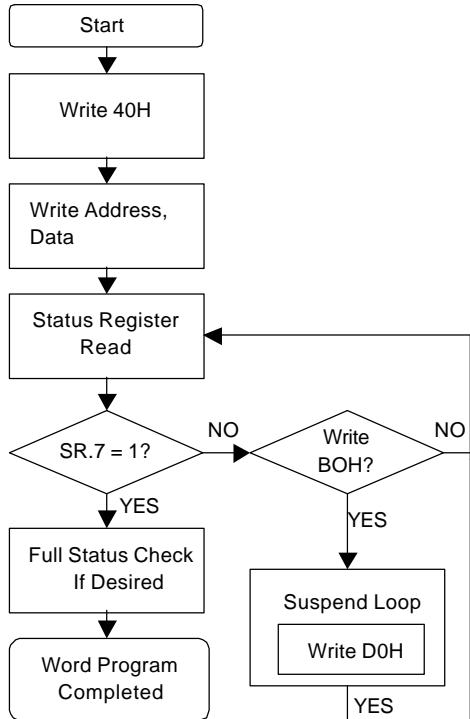
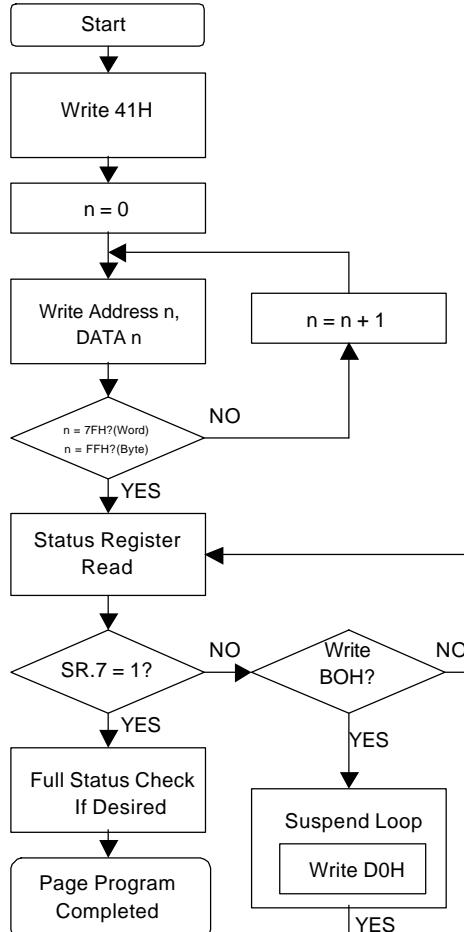
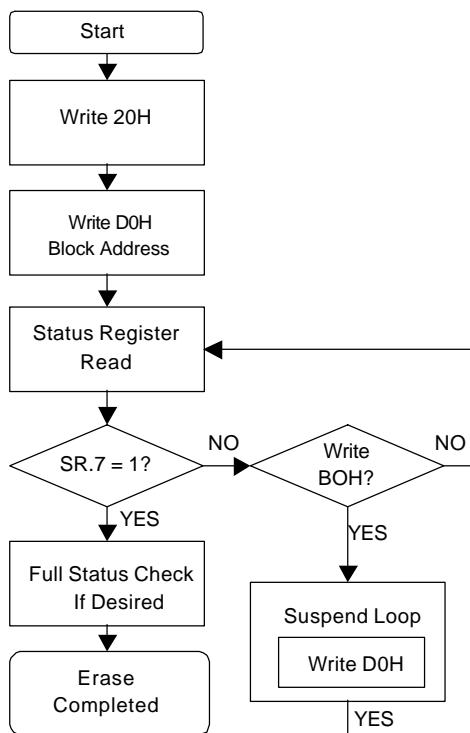
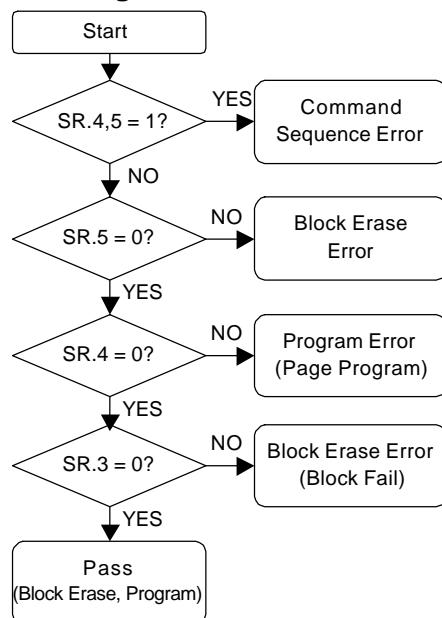
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67,108,864-BIT (8,388,608-WORD BY 8-BIT / 4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY

AC Waveforms for Device ID Read Operation with BBR(Back Bank Read)**AC Waveforms for Status Register Read Operation with BBR(Back Bank Read)**

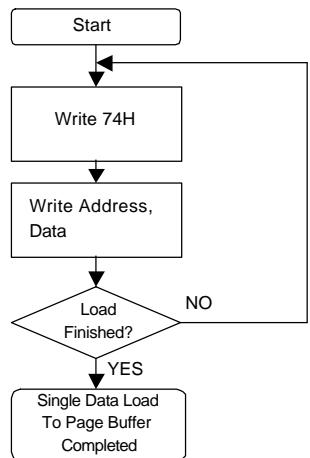
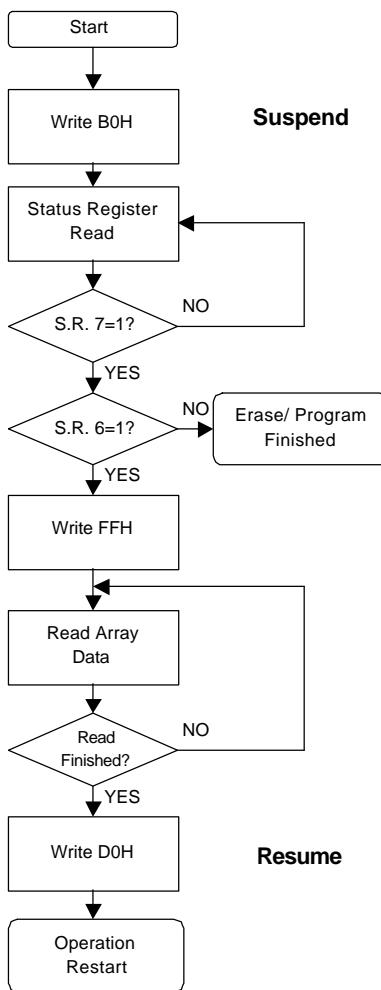
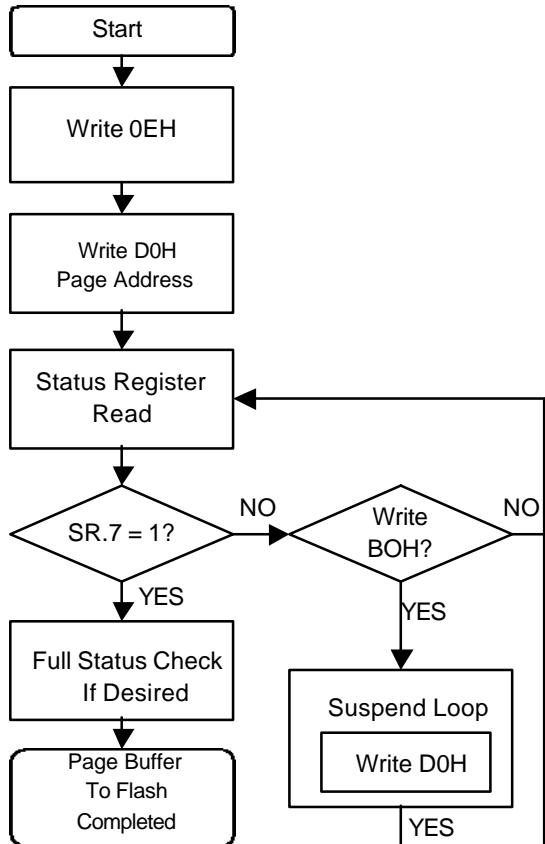
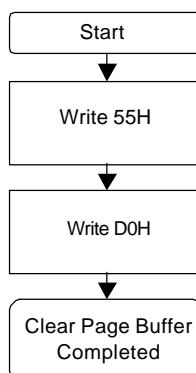
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**67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Word/Byte Program Flow Chart**Page Program Flow Chart****Block Erase Flow Chart****Status Register Check Flow Chart**

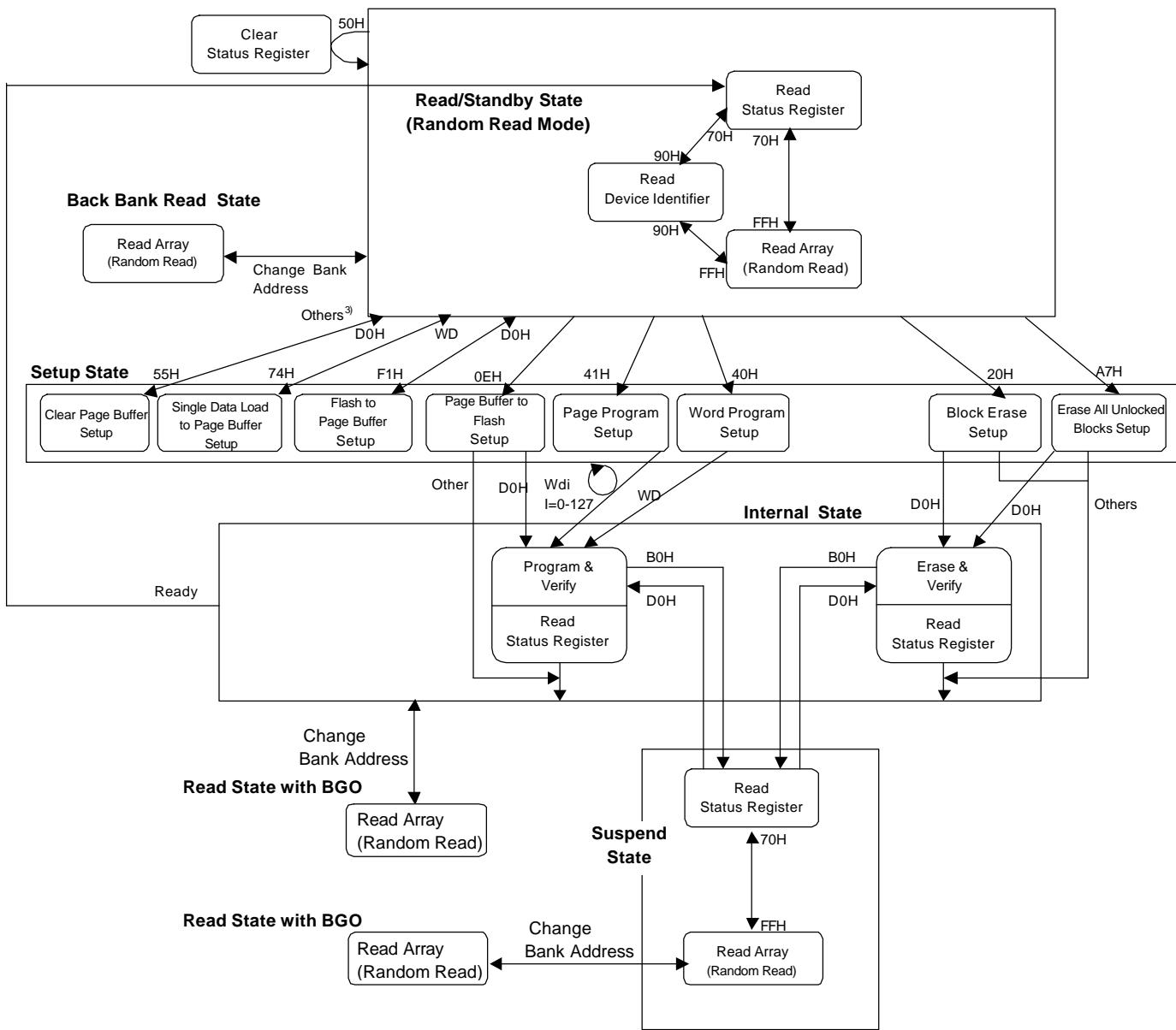
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67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY

**Single Data Load to Page Buffer
Flow Chart****Suspend / Resume Flow Chart****Page Buffer to Flash Flow Chart****Clear Page Buffer Flow Chart**

M5M29KB/T641AVP

**67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Operation Status (WP#=VIH)

1) In case of Page Read, F3H is used instead of FFH in Operation Status (F-WP#=VIH).

2) Once Page Read mode is set, Page Read mode is kept until power off or F-RP# is set to VIL.

3) After setting up Clear Page Buffer, D0H enables to clear Page Buffer.

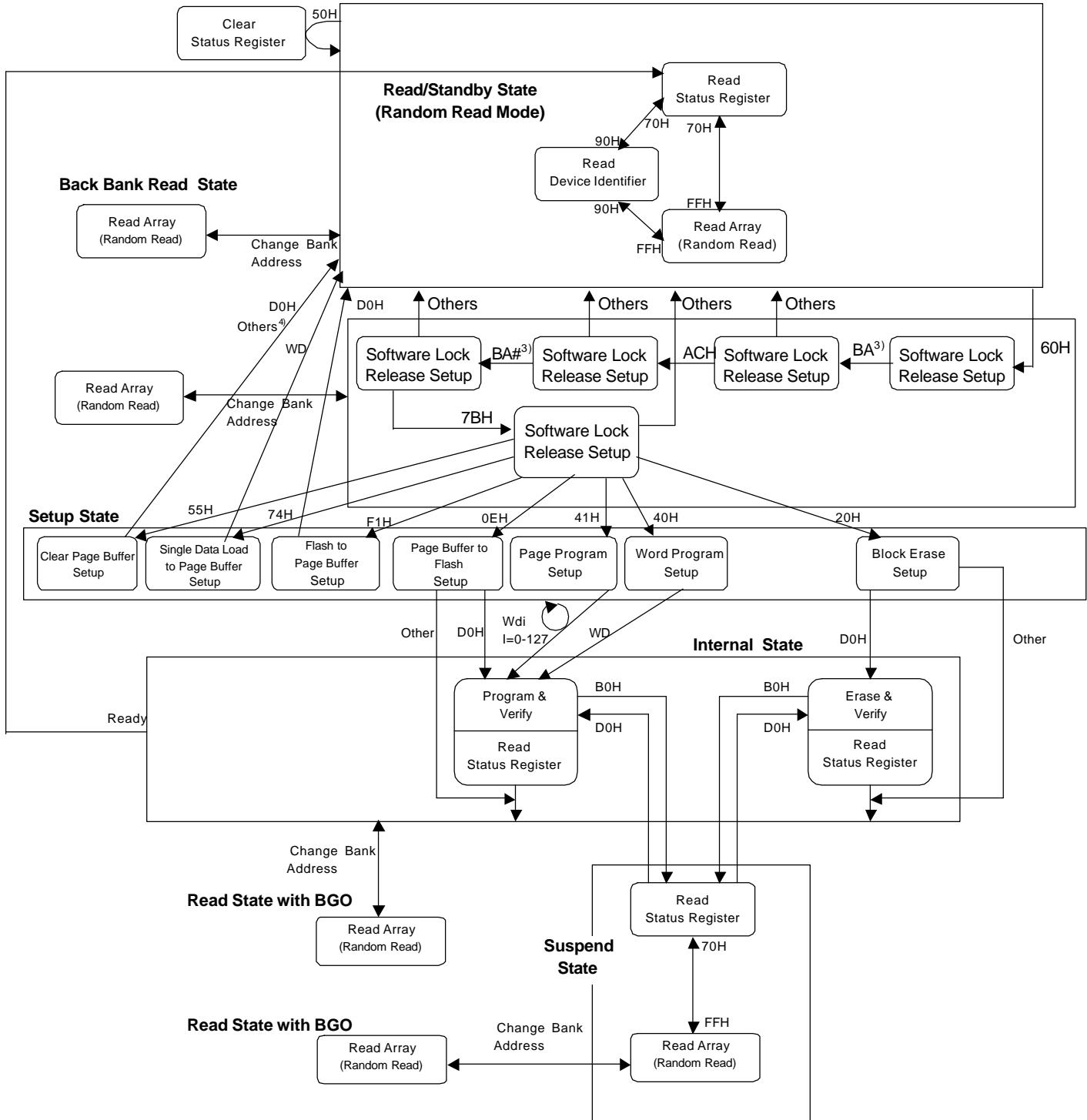
4) To access any bank during Erase All Unlocked Block results Status Register Read.

Although Read Status Register Command and Read Array Command can be issued under Suspend State, output data make no sense.

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CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Operation Status (WP#=VIL)



- 1) In case of Page Read, F3H is used instead of FFH in Operation Status (F-WP#=VIL).
 - 2) Once Page Read mode is set, Page Read mode is kept until power off or F-RP# is set to VIL.
 - 3) BA, BA#: Block Address, Block Address# (Shown in Command List(F-WP#=VIL) in detail).
 - 4) After setting up Clear Page Buffer, D0H enables to clear Page Buffer.

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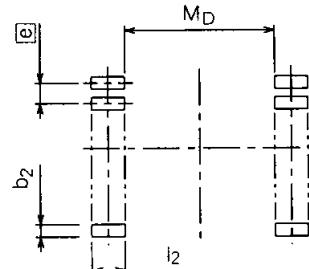
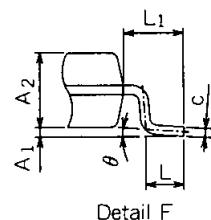
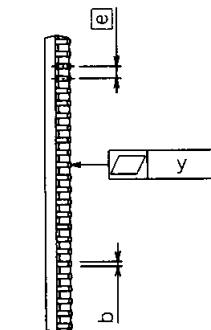
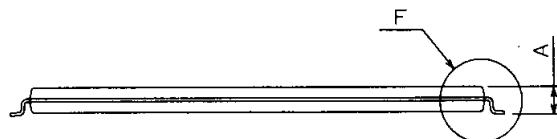
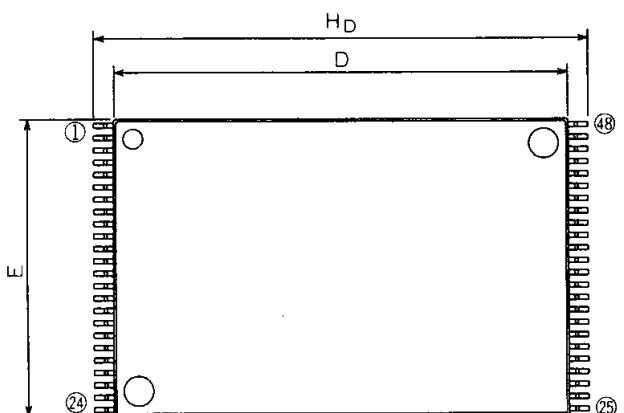
**67,108,864-BIT (8,388,608-WORD BY 8-BIT /4,194,304-WORD BY 16-BIT)
CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Package Dimension

48P3R-C

EIAJ Package Code	JEDEC Code	Weight(g)	Lead Material
TSOP I 48-P-1220-0.50	—		Alloy 42

Scale : 3/1



- Recommended Mount Pad

Symbol	Dimension in Millimeters		
	Min	Nom	Max
A	—	—	1.2
A ₁	0.05	0.125	0.2
A ₂	—	1.0	—
b	0.15	0.2	0.3
c	0.105	0.125	0.175
D	18.3	18.4	18.5
E	11.9	12.0	12.1
[e]	—	0.5	—
H _D	19.8	20.0	20.2
L	0.4	0.5	0.6
L ₁	—	0.8	—
y	—	—	0.1
θ	0°	—	10°
b ₂	—	0.225	—
l ₂	0.9	—	—
MD	—	18.6	—

M5M29KB/T641AVP

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CMOS 3.3V-ONLY, BLOCK ERASE FLASH MEMORY**

Renesas Technology Corp.

Nippon Bldg., 6-2, Otemachi 2-chome, Chiyoda-ku, Tokyo, 100-0004 Japan

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